

nanoscience and nanotechnology: small is different



www.nanoscience.imdea.org

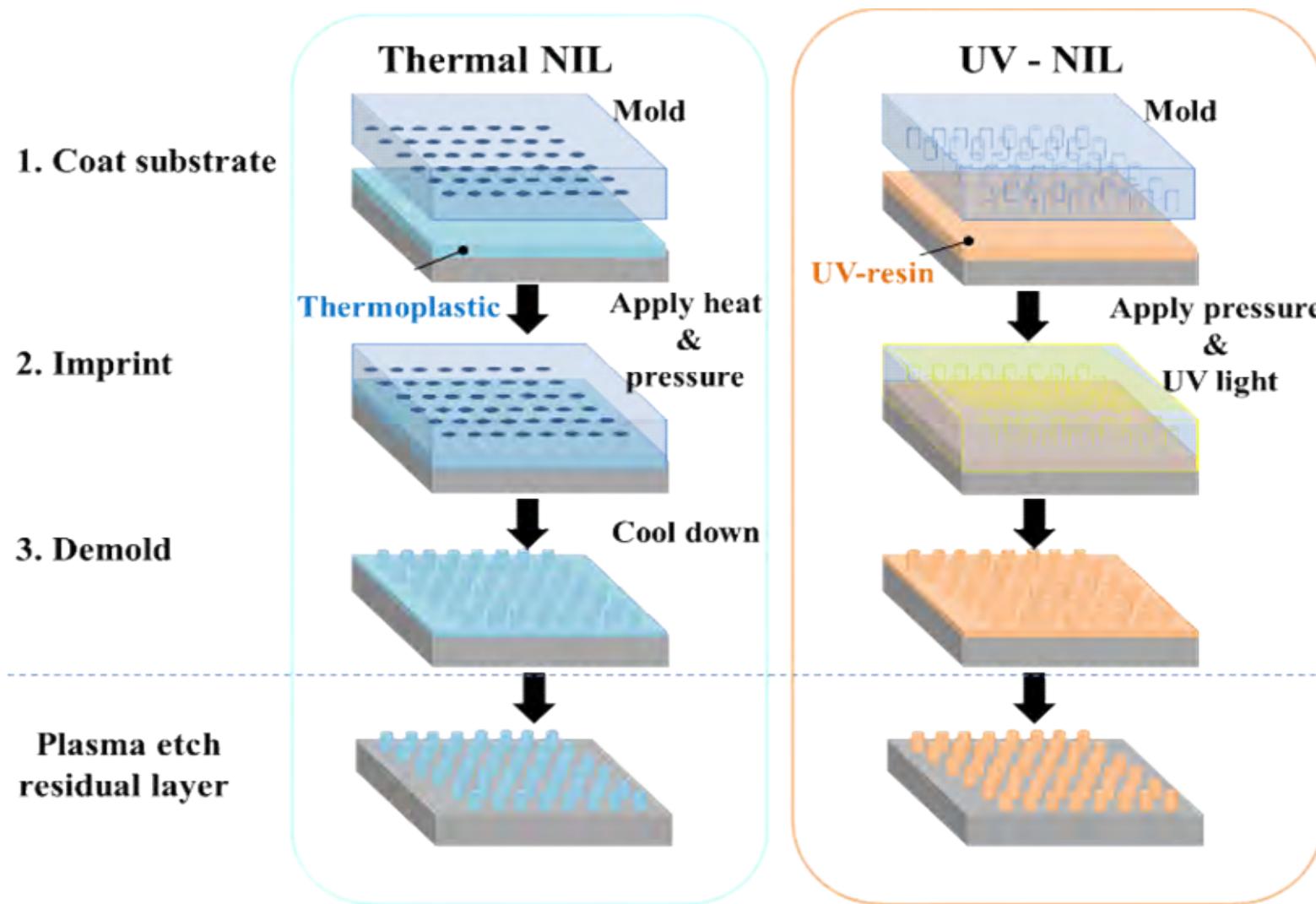
Nanoimprint lithography and hybrid processes *to produce complex nanostructures*

Isabel Rodríguez
i.rodriguez@imdea.org



Nano Imprint Lithography - NIL

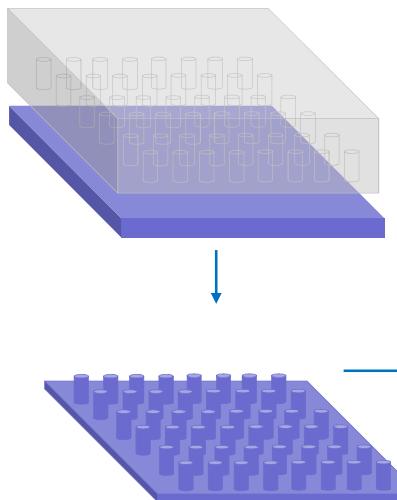
A replication process : Pattern transfer by mechanical deformation of a flowing resist material



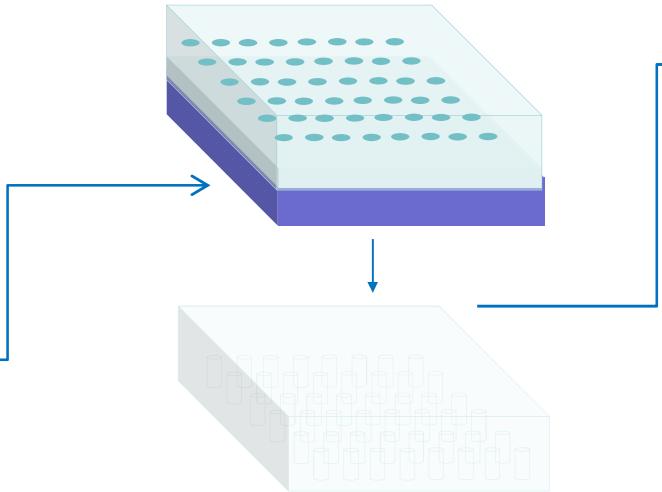
Soft –NIL

Thermal-NIL

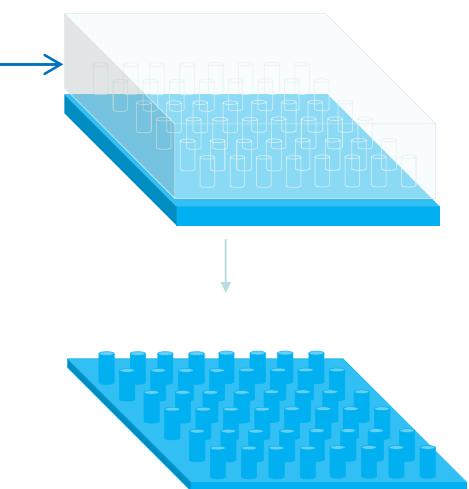
Hard Mold



Soft lithography



Soft NIL



IPS

Intermediate polymer stamp

Soft Mold

PDMS
PFPE

Patterned polymer

Soft –NIL:

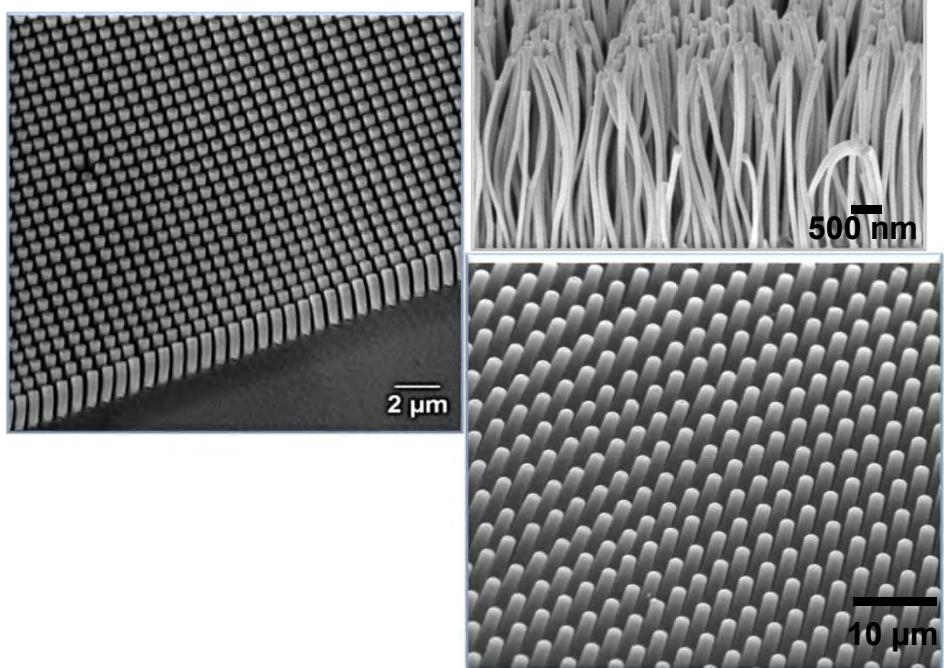
- Sequential action of peeling the mold from substrate
- High gas permeability
- Conformal contact to substrate
- Low surface energy

PDMS: Polydimetilsiloxane

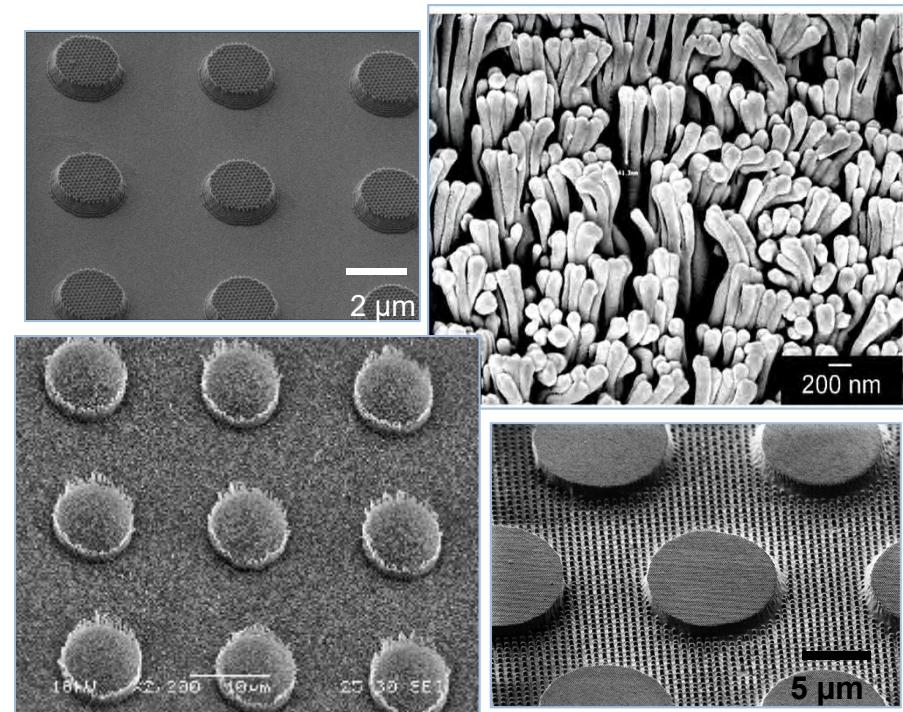
PFPE: Polyurethane based on perfluoropolyether

Key Technological Expertise

High Aspect Ratio Topographies



Complex Hierarchical Topographies

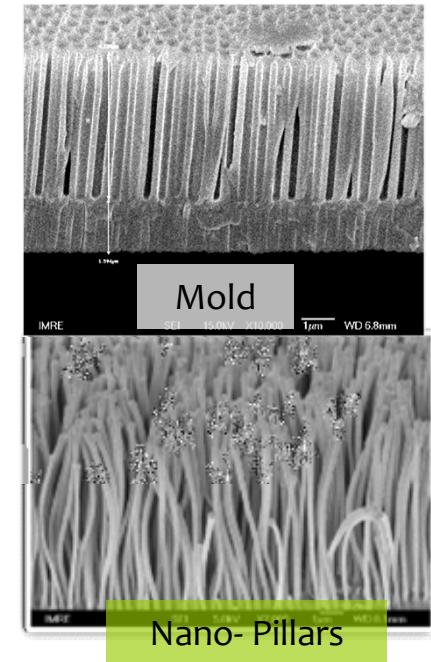
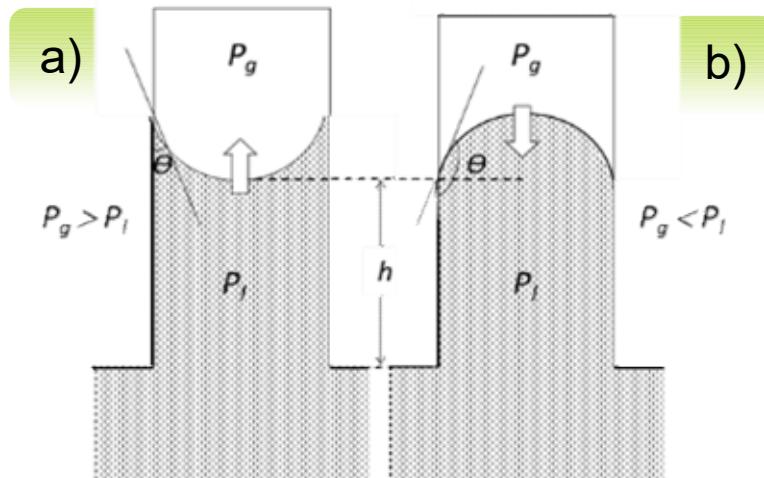


High Aspect Ratio NIL

Laplace pressure - Capillary forces



$$\Delta P_c = P_g - P_l = \frac{2 \gamma \cos\theta}{r}$$



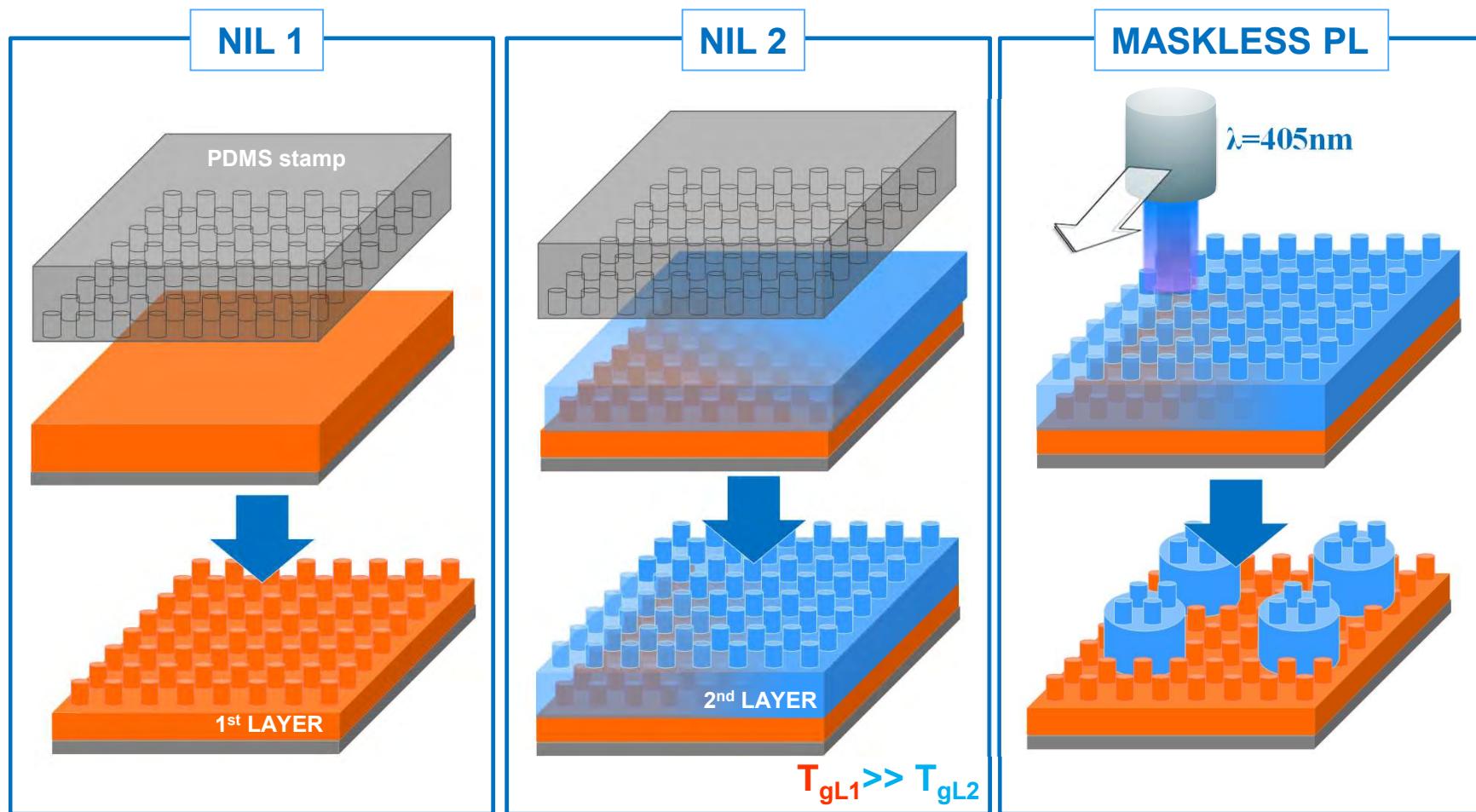
- a) polymer wets the capillary ($\theta < 90^\circ$)
- b) polymer does not wet the capillary ($\theta > 90^\circ$)

Lucas-Washburn equation:

$$\frac{dh}{dt} = \frac{r \gamma \cos\theta}{4\eta h} \quad t = \frac{2 \eta h^2}{r \gamma \cos\theta}$$

γ_p - surface tension of the viscous polymer
 η - the viscosity
 θ - the solid-liquid contact angle
 r - the capillary radius.

Hybrid fabrication process: NIL + PL

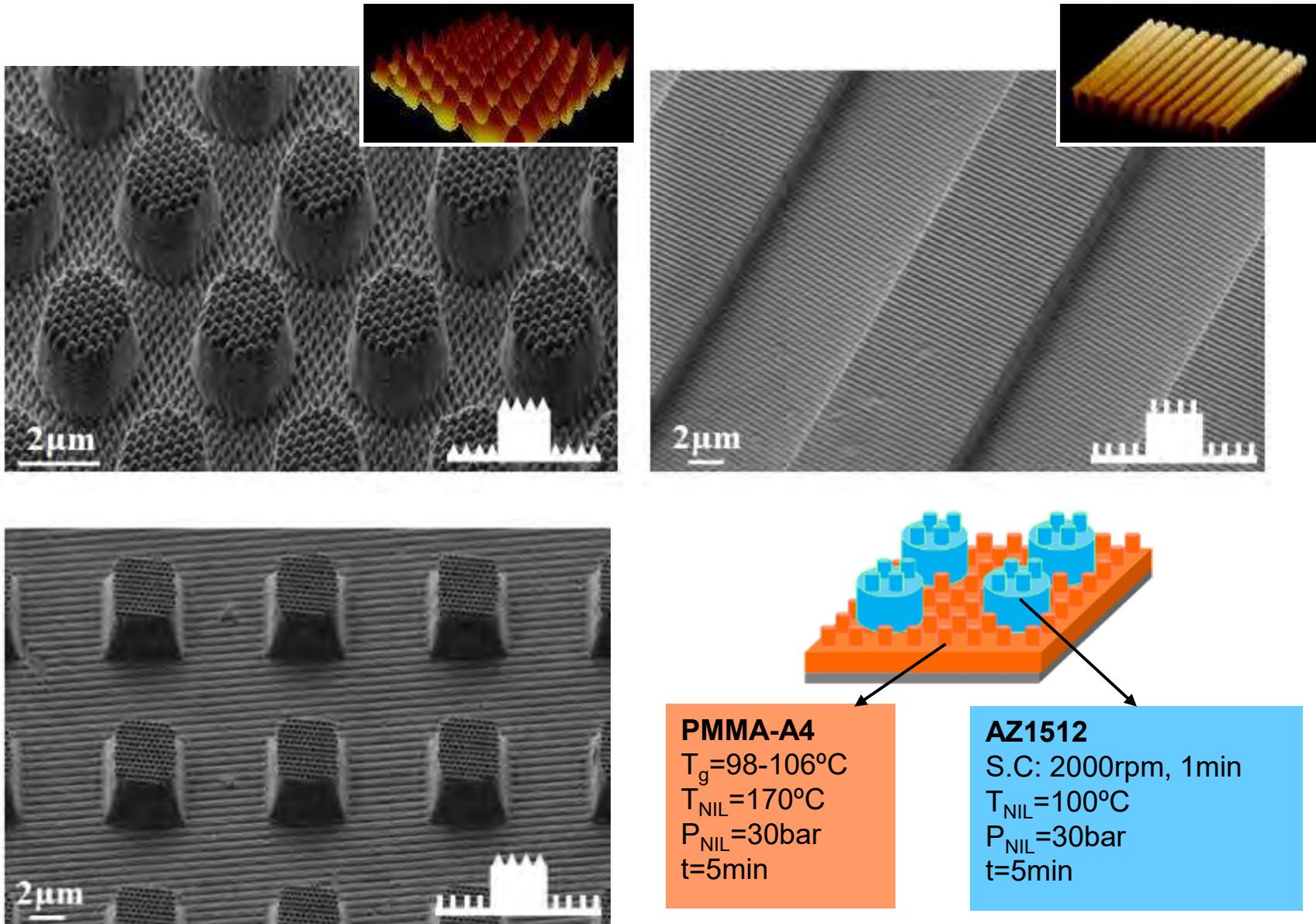


NIL: Nanoimprint Lithography ; PL: Photolithography



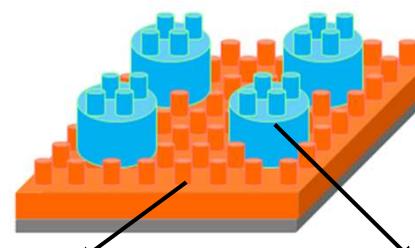
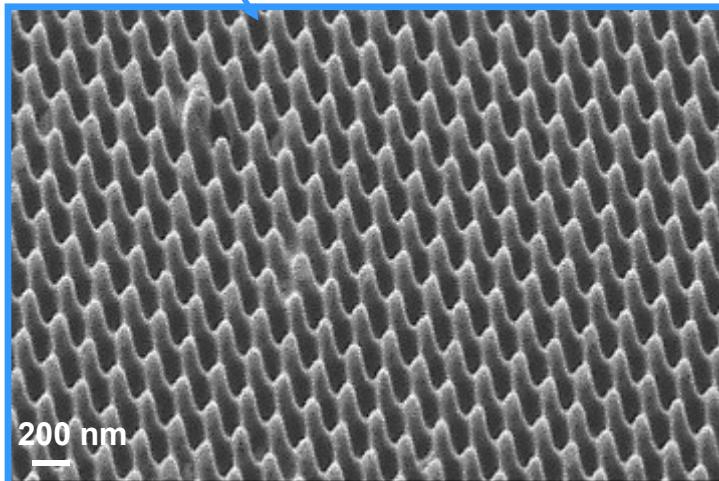
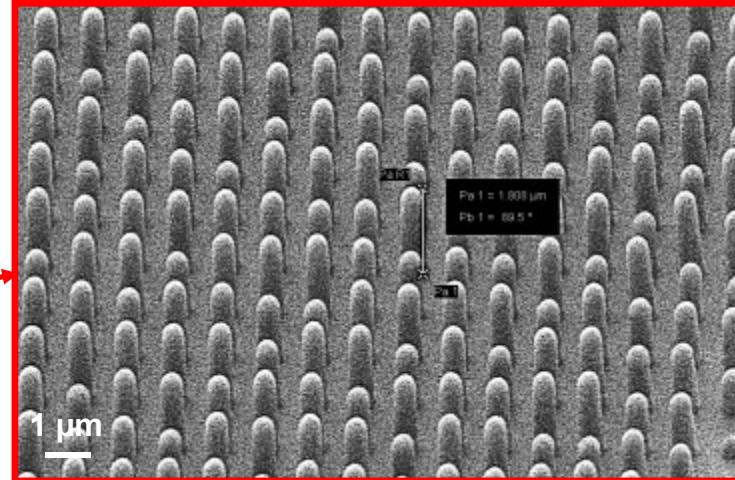
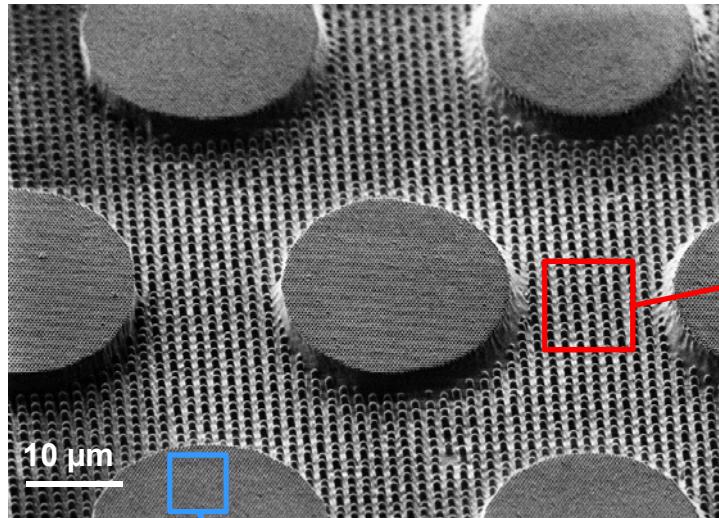
Micro & Nano Hierarchical Structures

1ST LAYER: THERMOPLASTIC



Micro & Nano Hierarchical Structures

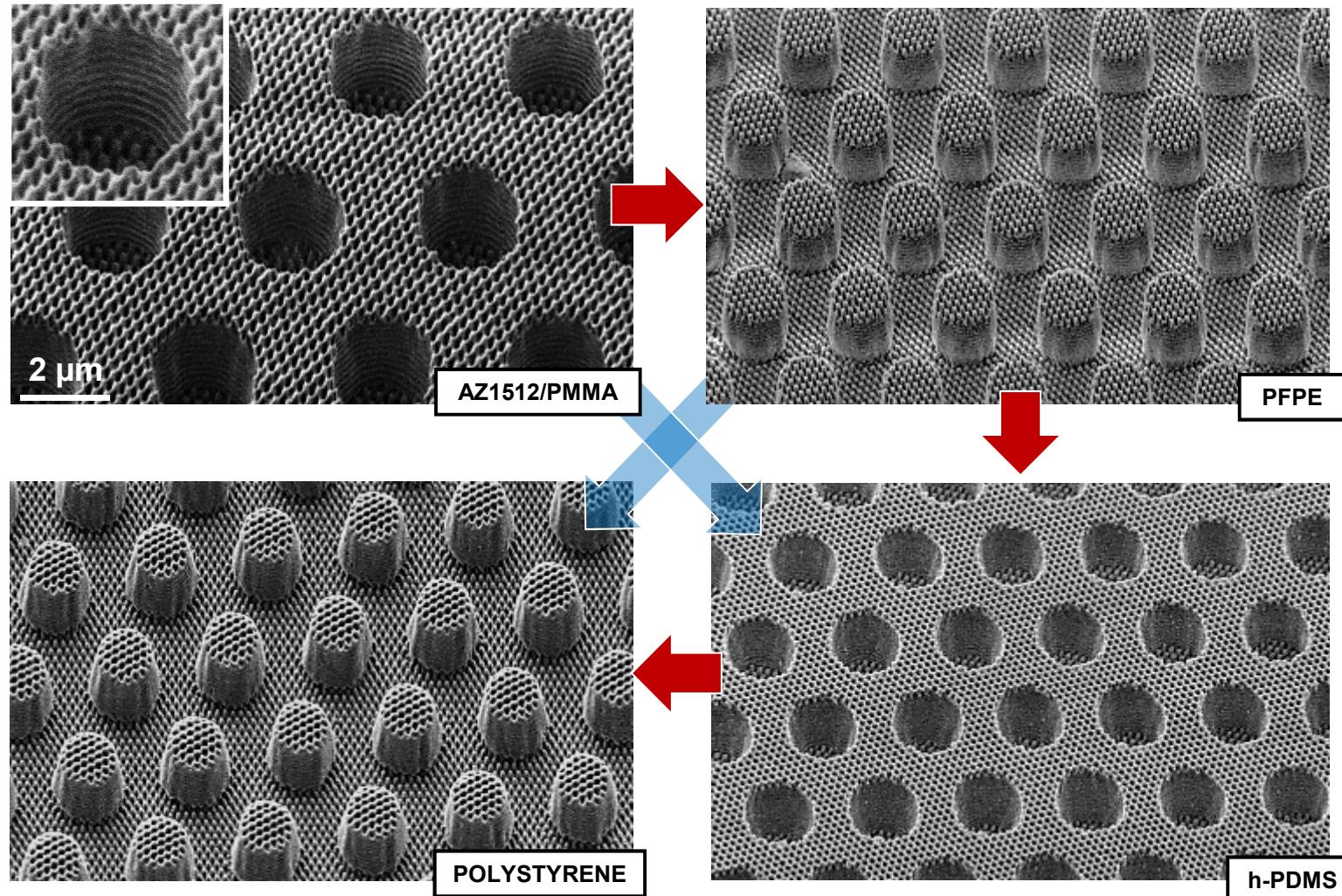
1ST LAYER: THERMOSET



EpoTek
 $T_{\text{UV-NIL}}=60^\circ\text{C}$
 $P_{\text{NIL}}=30\text{bar}$
 $t=5\text{min}$

AZ1512
S.C: 2000rpm, 1min
 $T_{\text{NIL}}=100^\circ\text{C}$
 $P_{\text{NIL}}=30\text{bar}$
 $t=5\text{min}$

Soft-NIL - Polymer replication

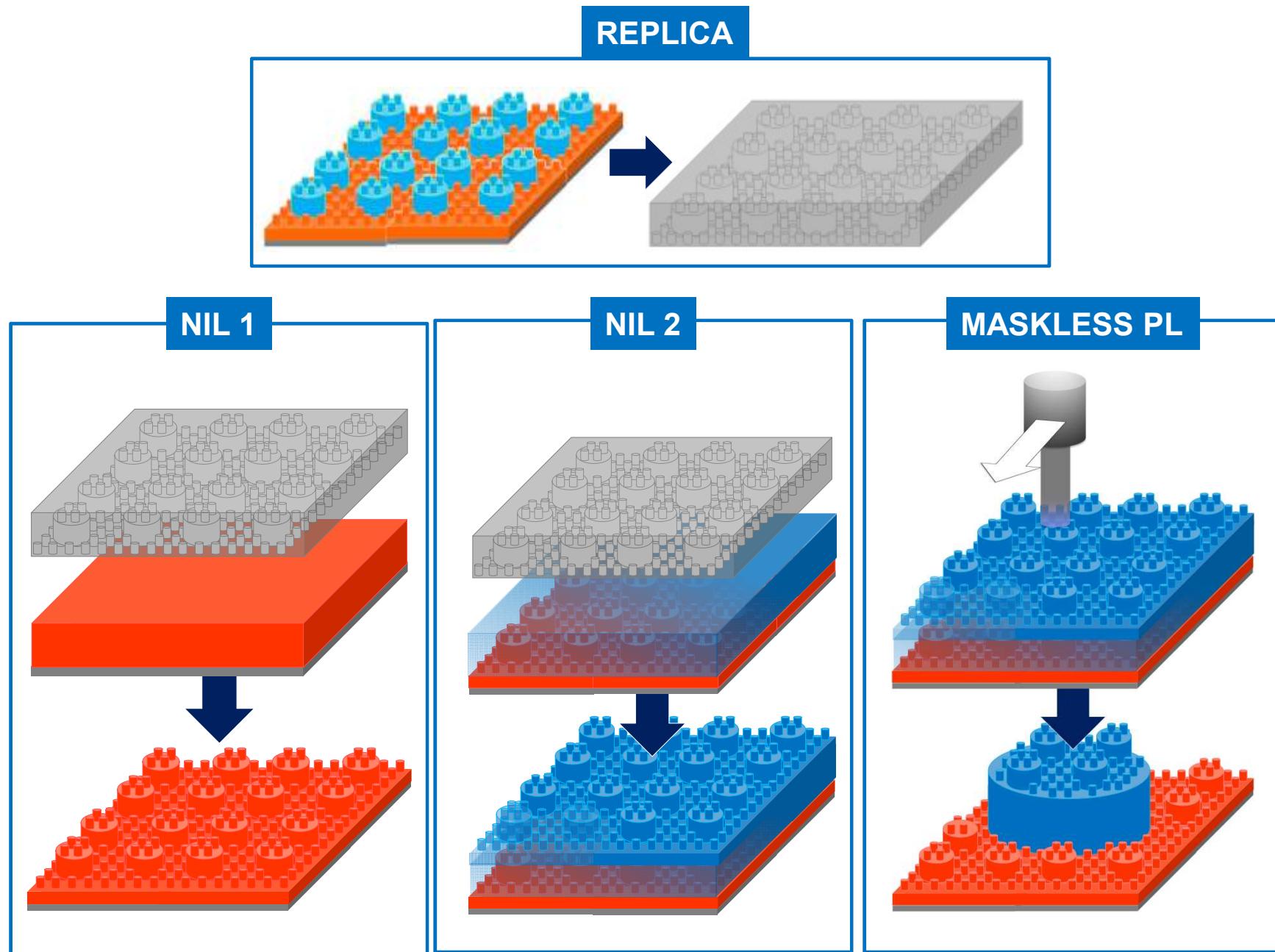


PFPE - Perfluoropolyether

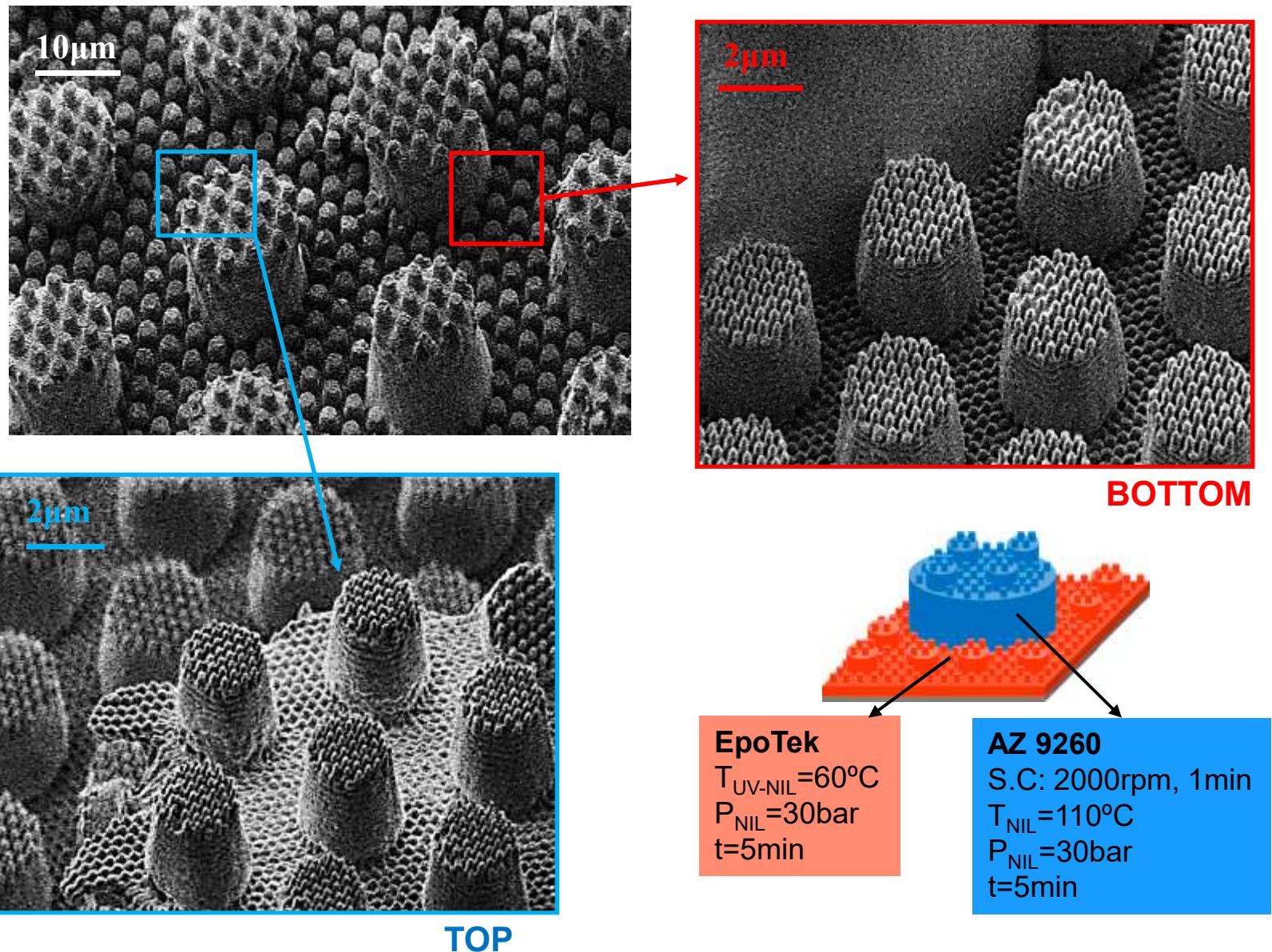
PMMA - Poly(methyl methacrylate)

PDMS - Polydimethylsiloxane

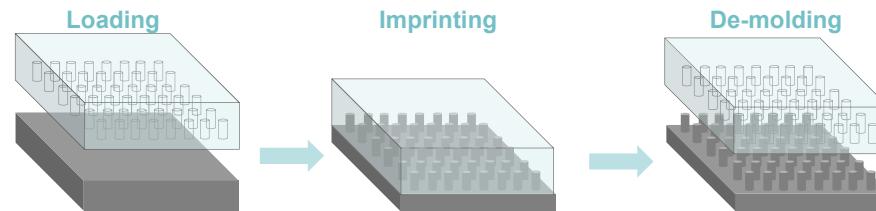
Multilevel Hierarchical Structures



Multilevel Hierarchical Structures



Nanoimprint Lithography (NIL) Tools

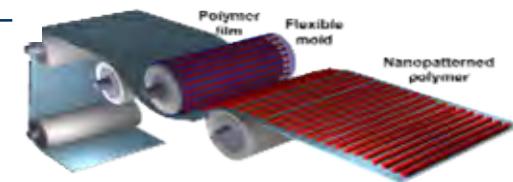


3" wafers - UV & Thermal NIL
Thermosets & thermoplastic materials

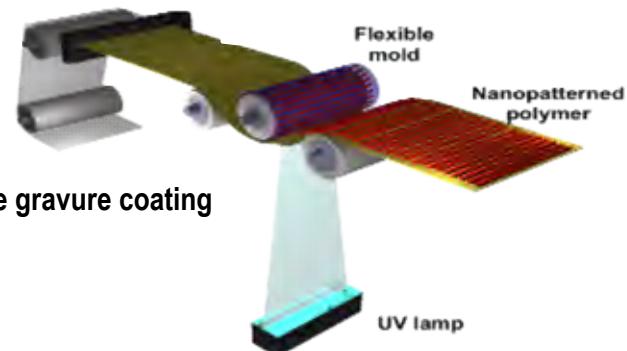
Obducat Eitre® E3



Thermal -NIL



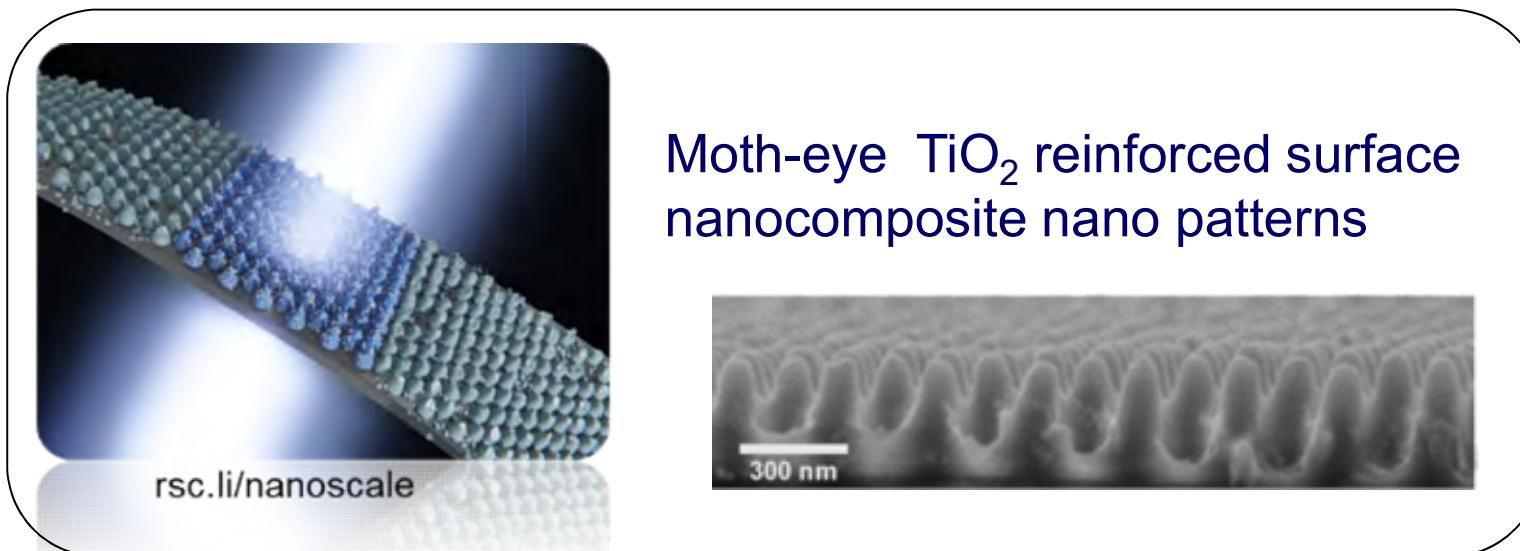
UV-NIL



Reverse gravure coating

Roll to Roll NIL - Pilot facility for scale-up processing (5 m/min)

Moth-eye biomimetic anti-reflective surfaces



Nanoscale

PAPER

Check for updates

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Single-imprint moth-eye anti-reflective and self-cleaning film with enhanced resistance†

Iván Navarro-Baena,^{1,2*} Alejandra Jacobo-Martín,^{1,2*} Jaime J. Hernández,^{1,2} José R. Castro Smirnov,² Felipe Viela,^{1,2*} Miguel A. Monclús,^{1,2} Manuel R. Osorio,^{1,2} Jon M. Molina-Aldareguía,^{1,2} and Isabel Rodríguez,^{1,2}

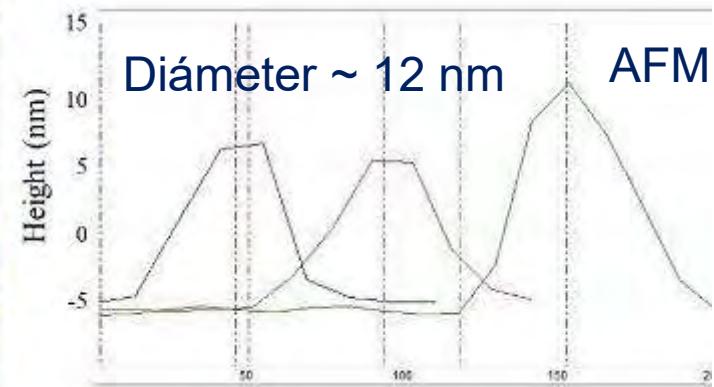
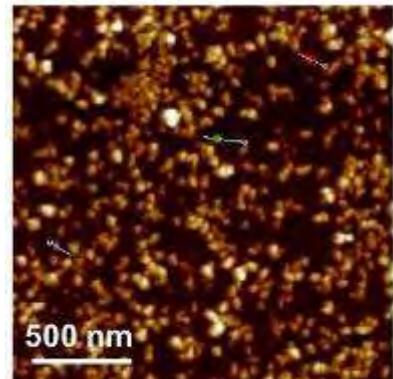
TiO₂ Surface Nanocomposite

Preparation of polymer nanocomposite

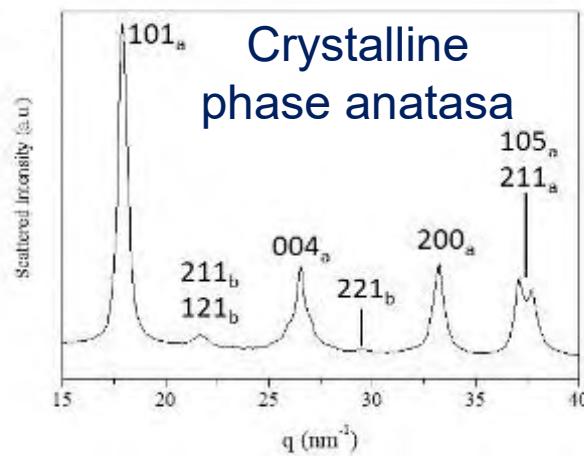
TiO₂ nanoparticles: Hydrothermal synthesis



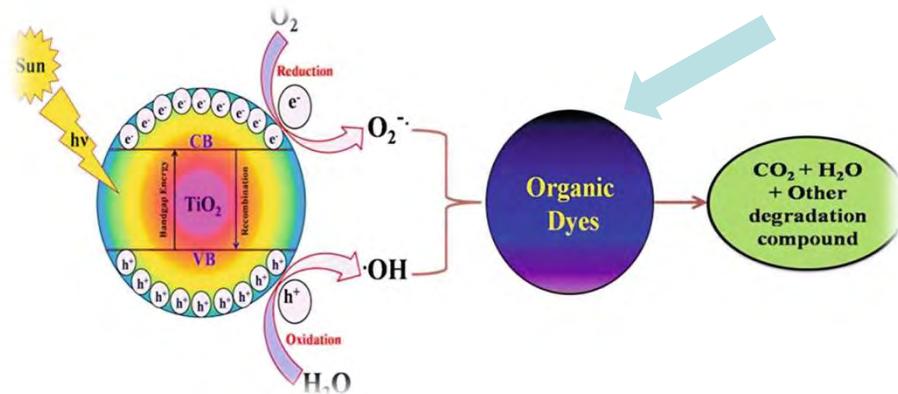
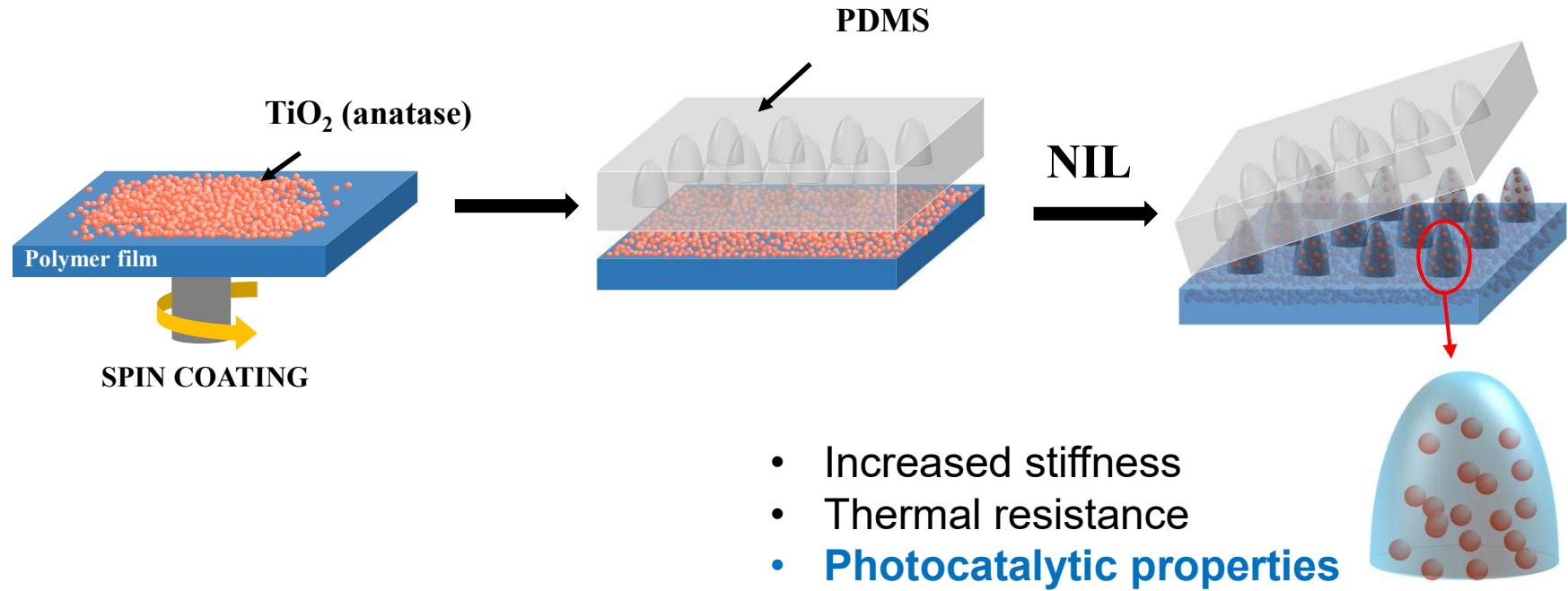
Coloidal suspensión



WAXS

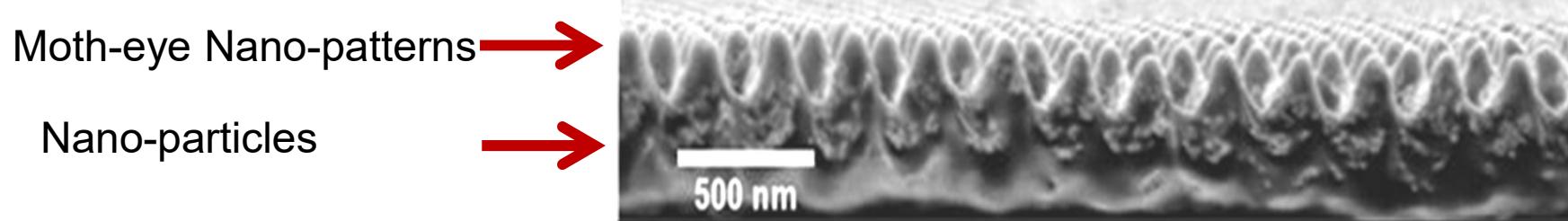
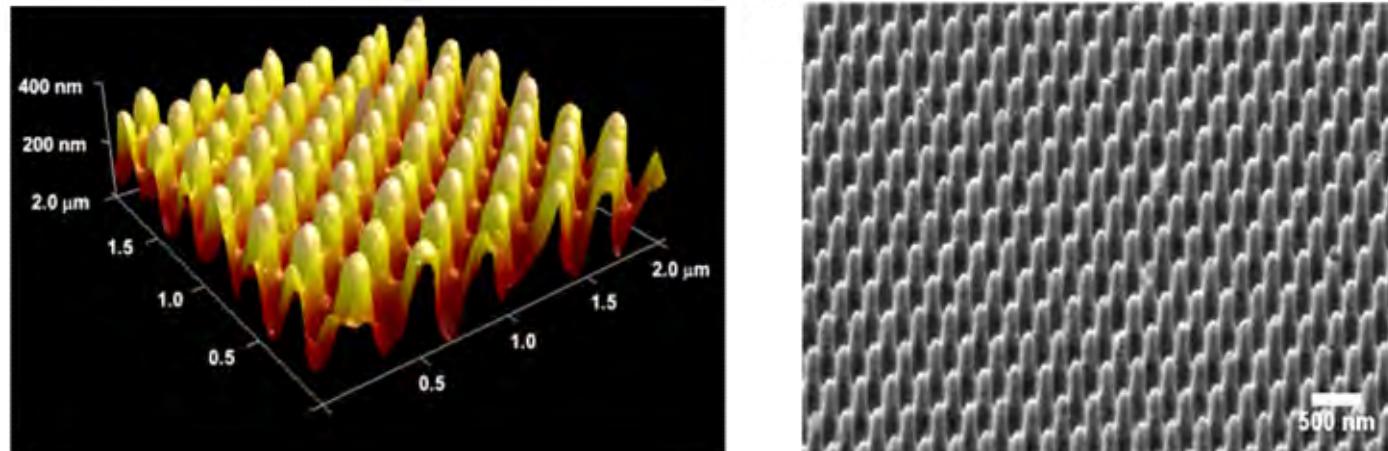


Anti-reflective surface nanocomposite



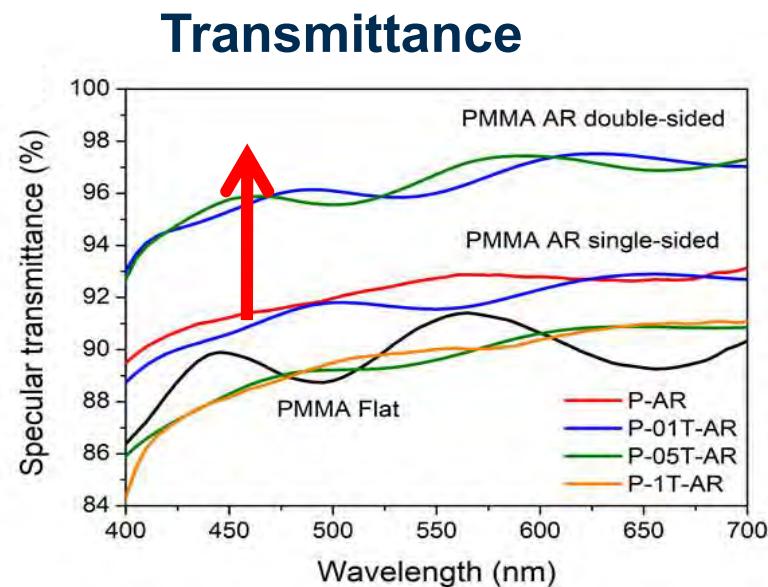
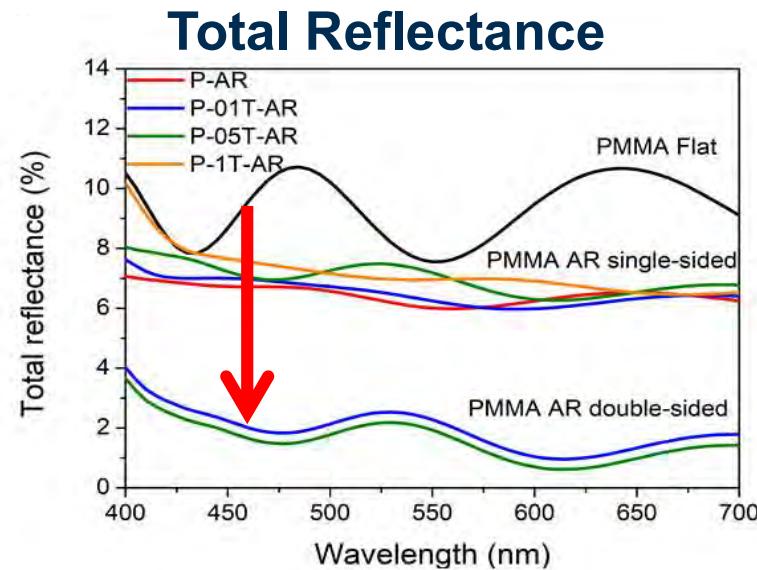
Moth-eye imprinted topography

Morphology: SEM & AFM images

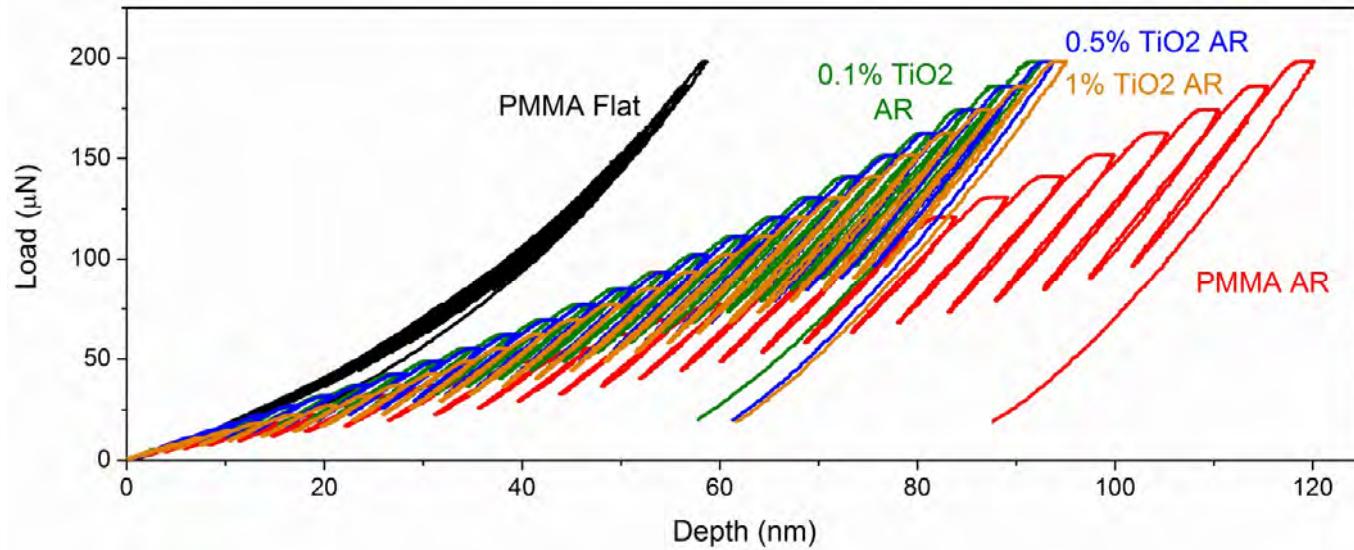


- High fidelity replication of the master mold on PMMA Nanocomposites
- Good nanoparticles dispersion
- Embedded particles within the polymer

Moth-eye optical characterization



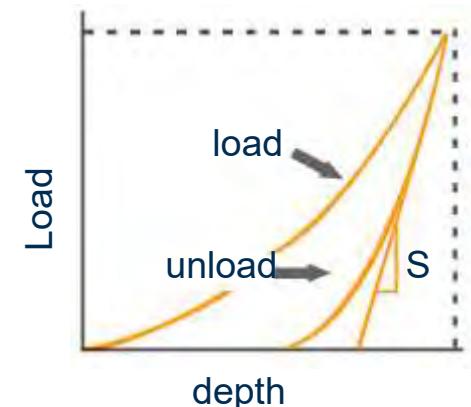
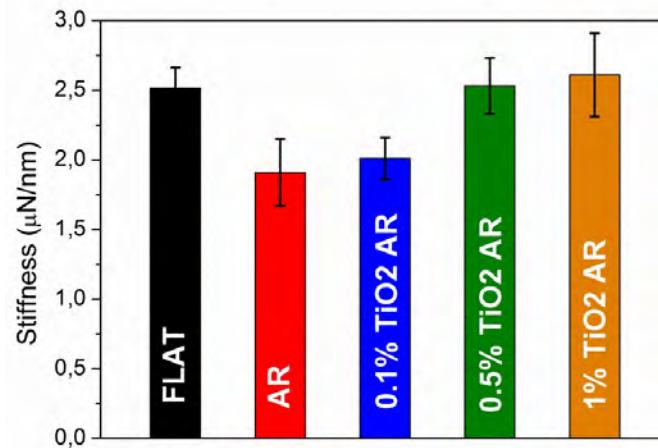
Mechanical behavior: Nanoindentation



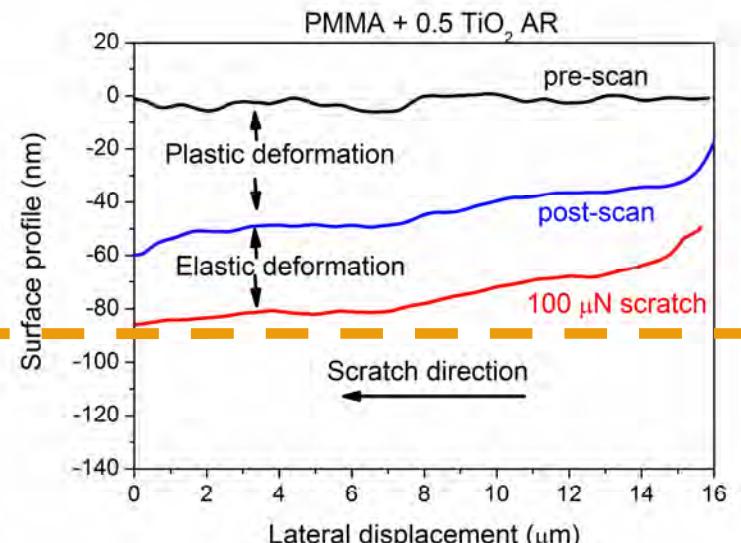
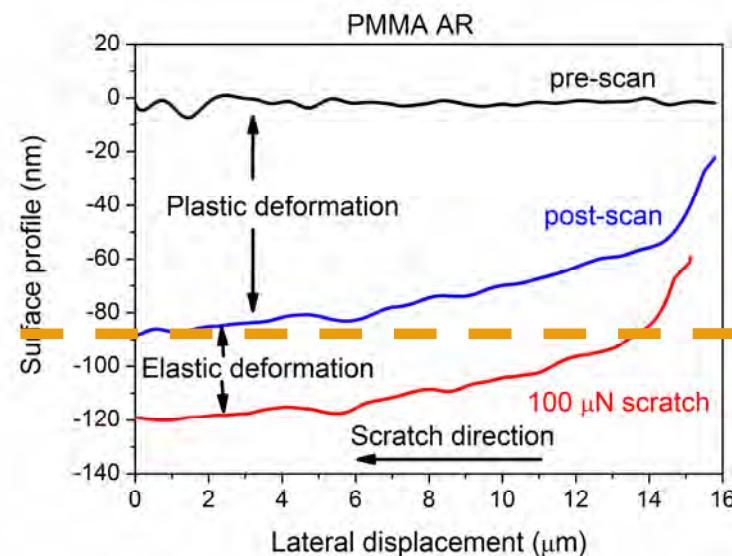
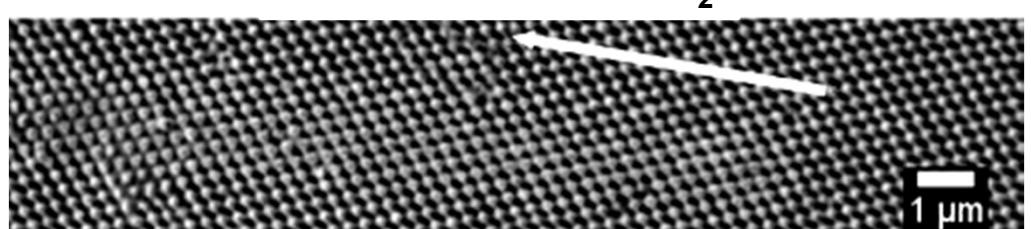
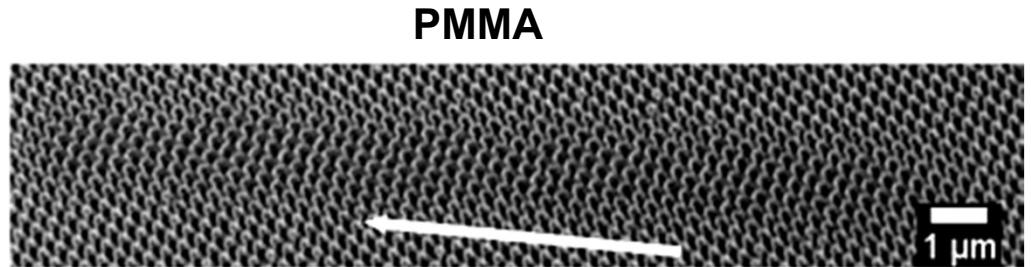
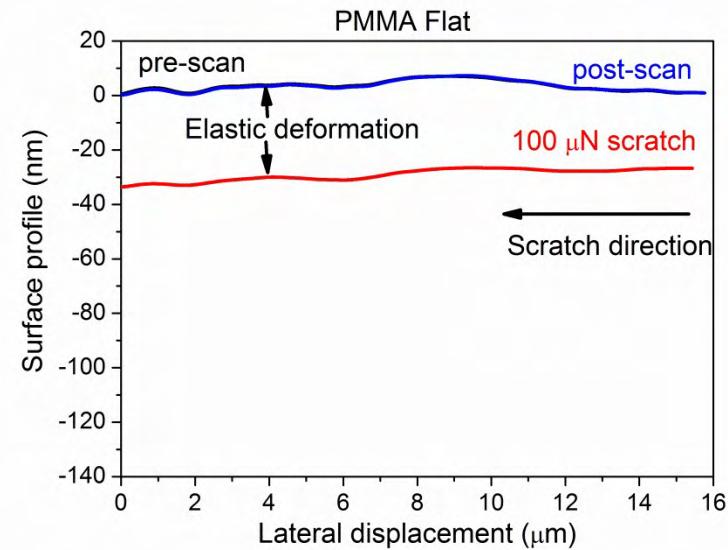
20 load/unload cycles until maximum load of 200 μN

Stiffness

Slope of the curves
in the elastic region
(maximum of 10 nm)

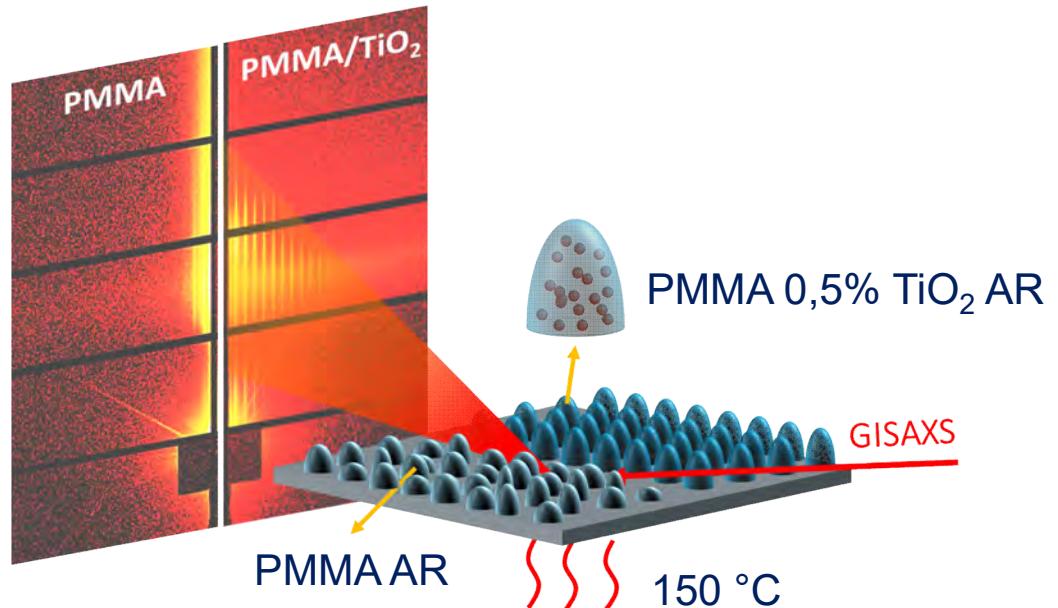


Mechanical resistance : Nanoscratch

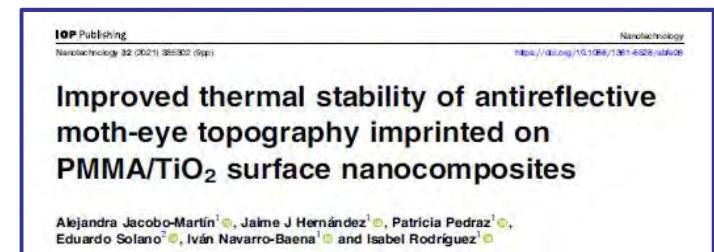
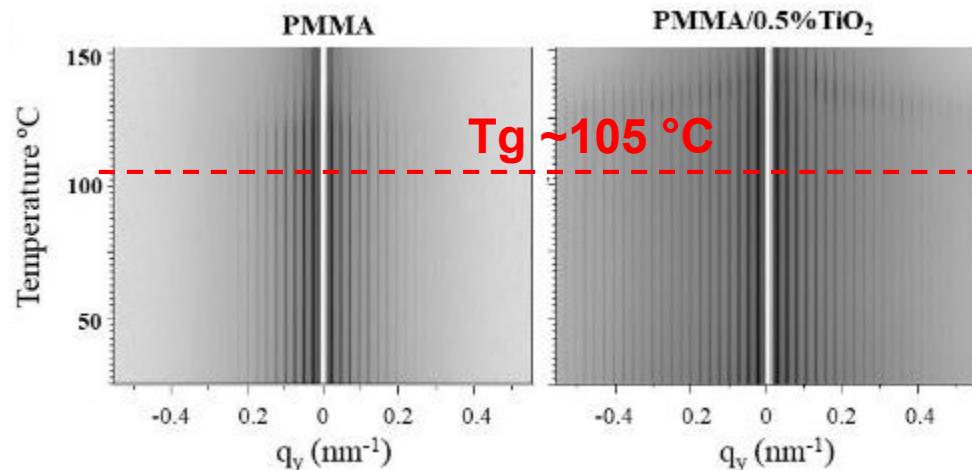


Thermal stability of AR patterns

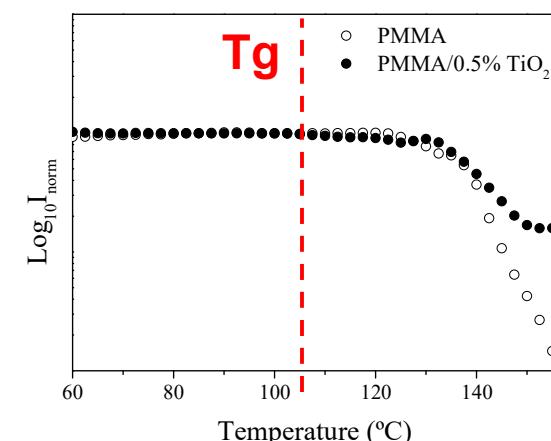
Grazing Incidence Small Angle X-ray Scattering: GISAXS



Integrated scattered intensity plots

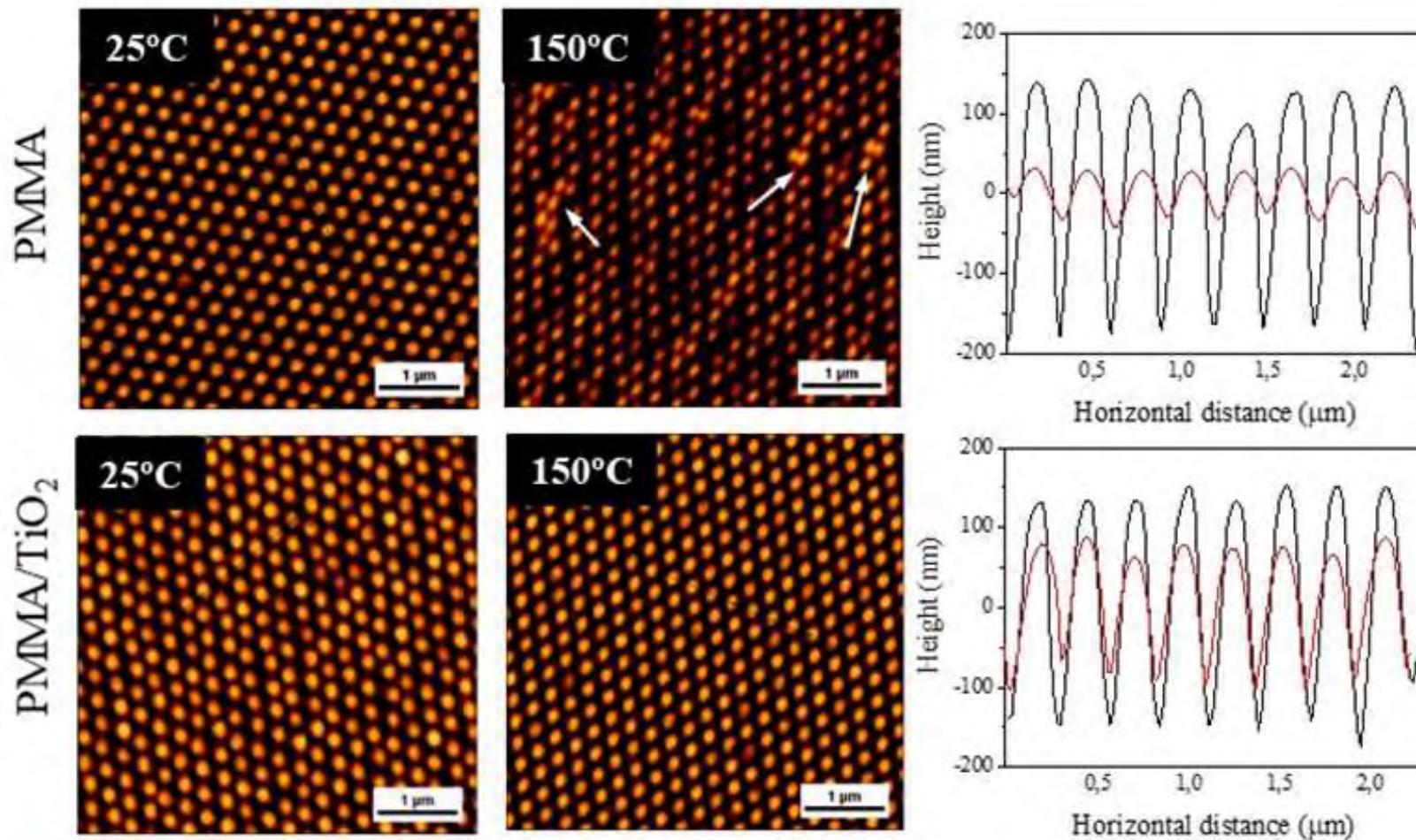


Distortions on the AR pattern
↓
Changes on the diffraction pattern



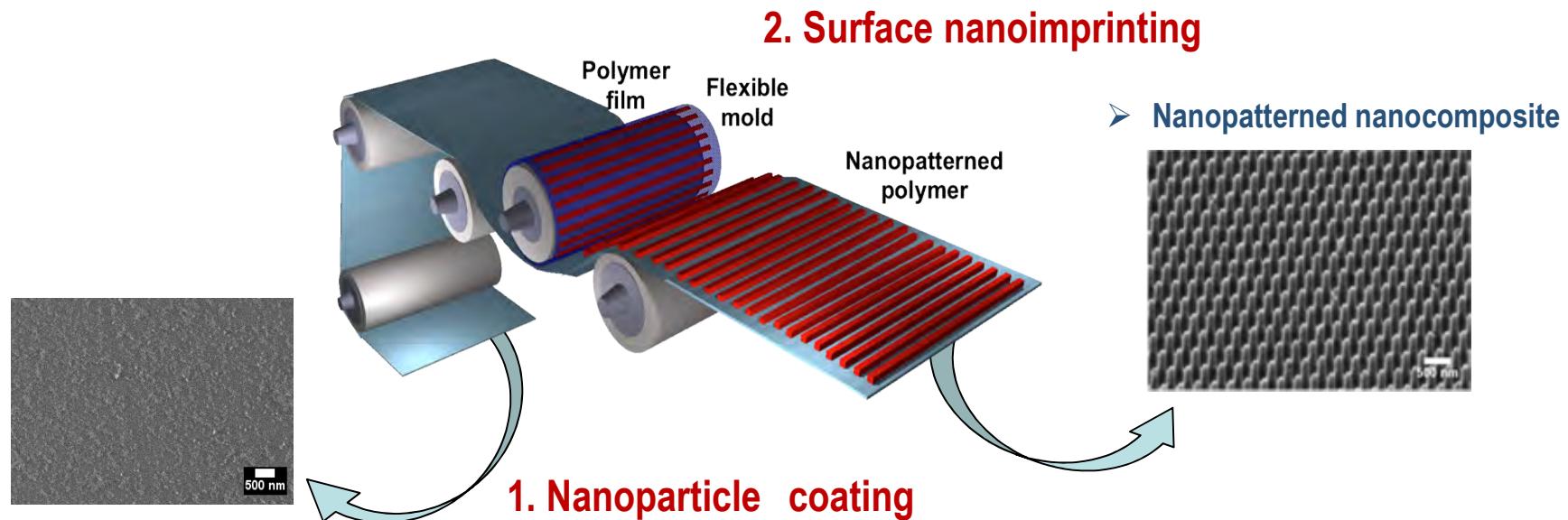
Improved thermal stability

Moth-eye PMMA/TiO₂ surface nanocomposites

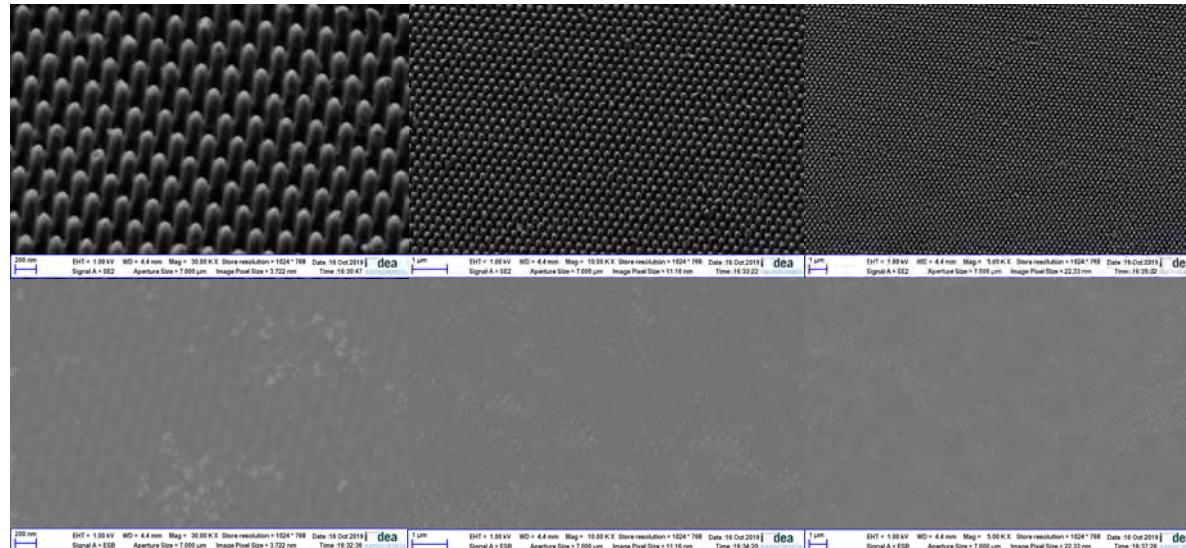


“anchoring effect of the TiO₂ NP to the polymer chain mobility” – pattern stability

Continuous R2R process

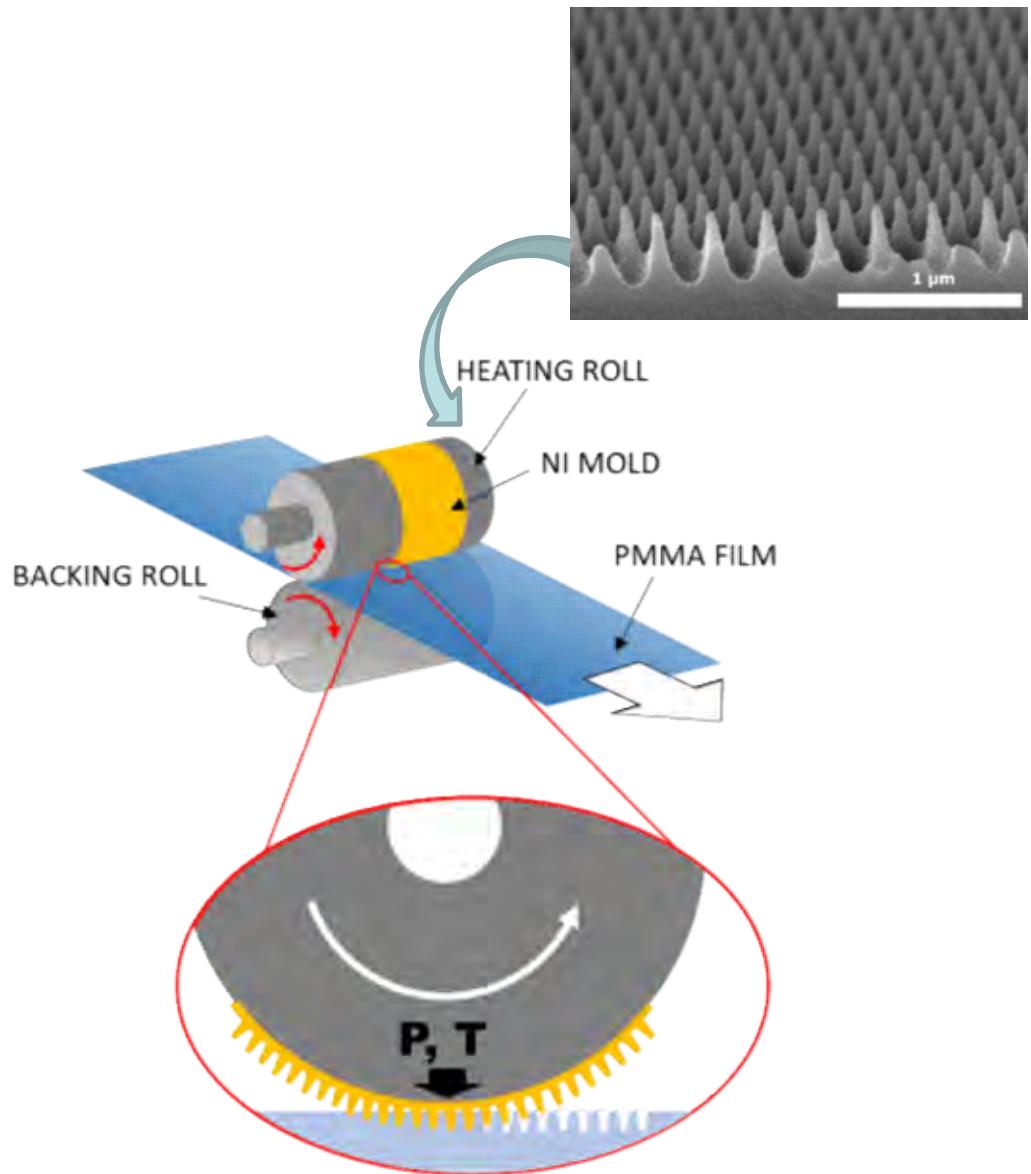
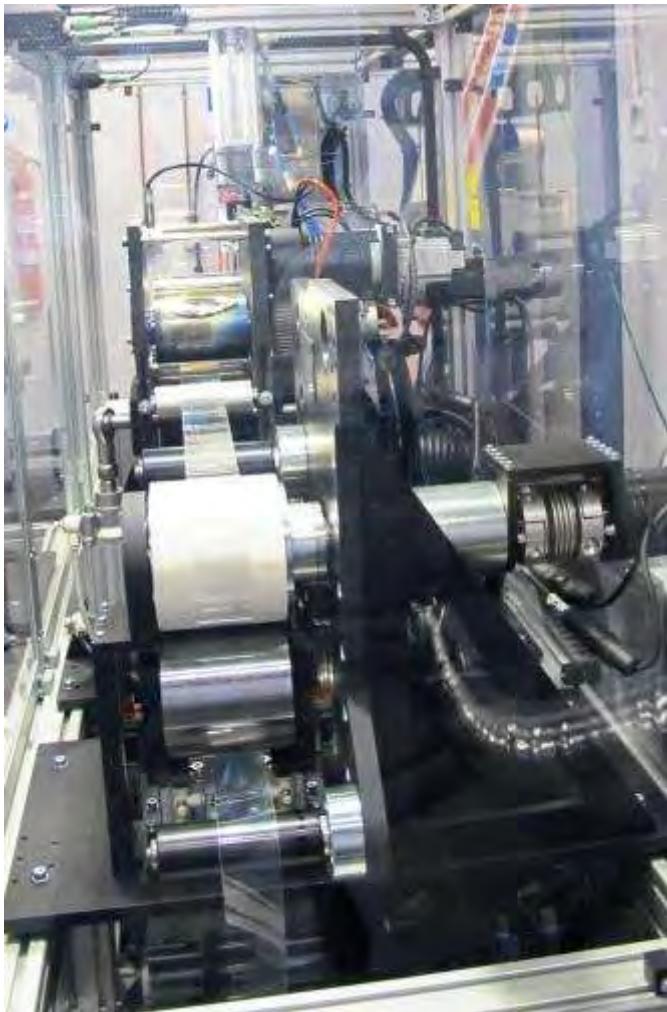


PET + PMMA + 025 % TiO₂ ARC (R2R)



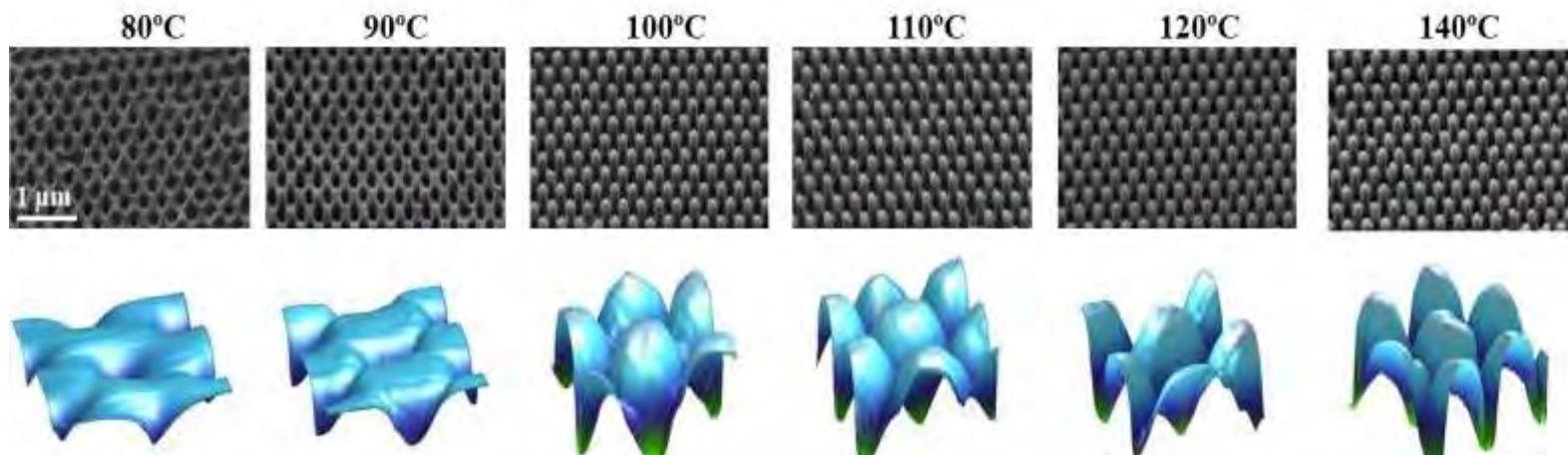
Patent : Polymeric composites with functional surfaces EP3436233B1 0000000

Thermal R2R imprinting of moth-eye non-reflective films

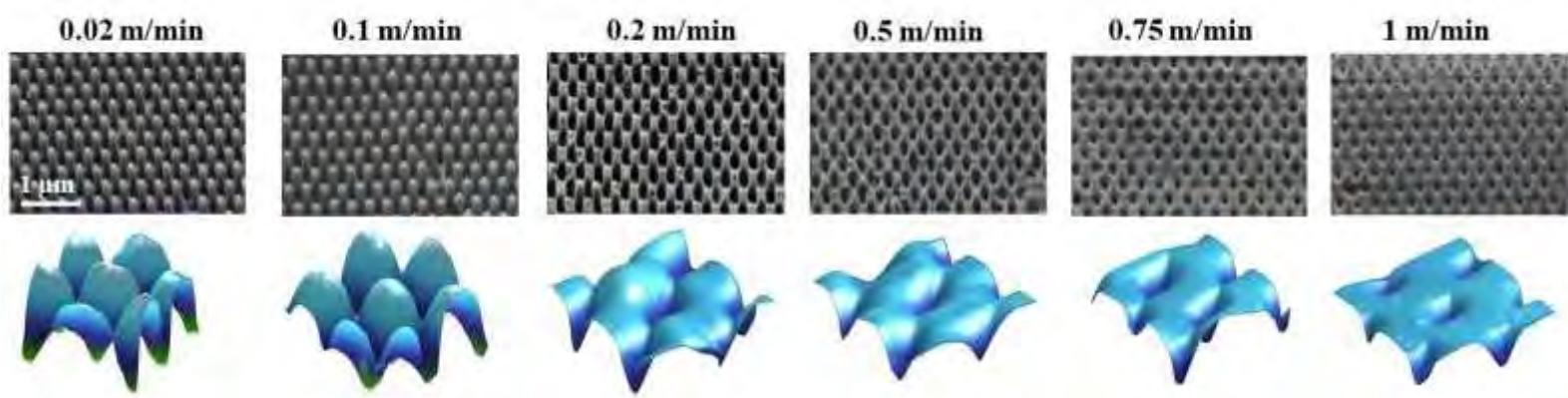


Thermal R2R imprinting of moth-eye non-reflective films

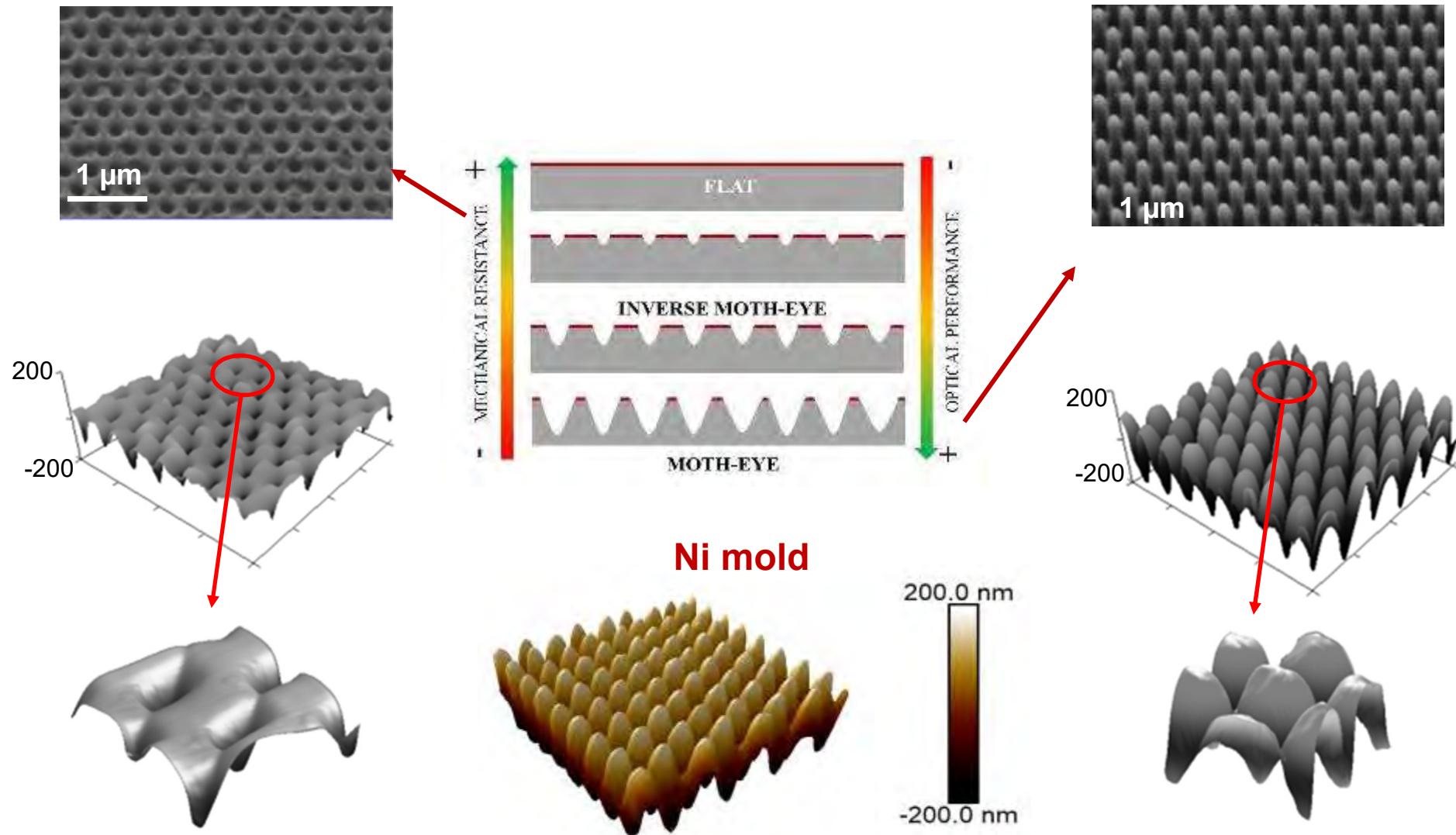
@ Variable temperature



@ Variable speed



Thermal R2R imprinting of moth-eye non-reflective films

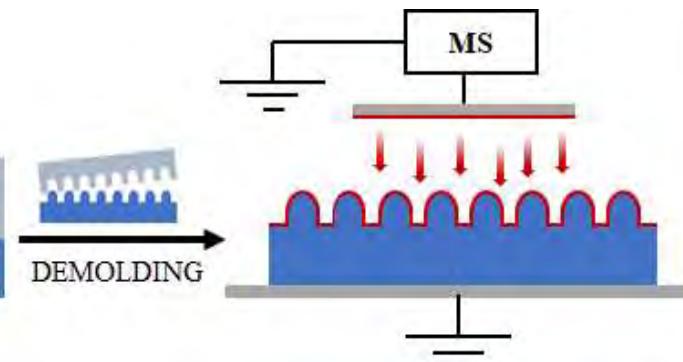


TiO₂-PMMA Moth-eye MS coating

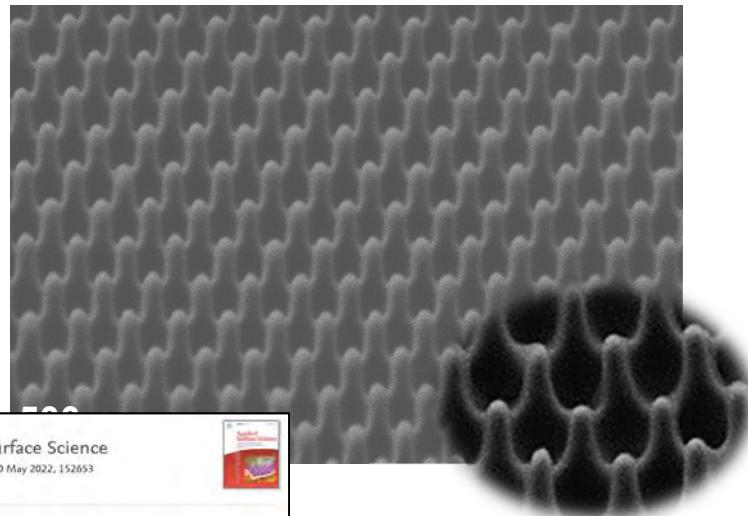
NANOIMPRINT LITHOGRAPHY



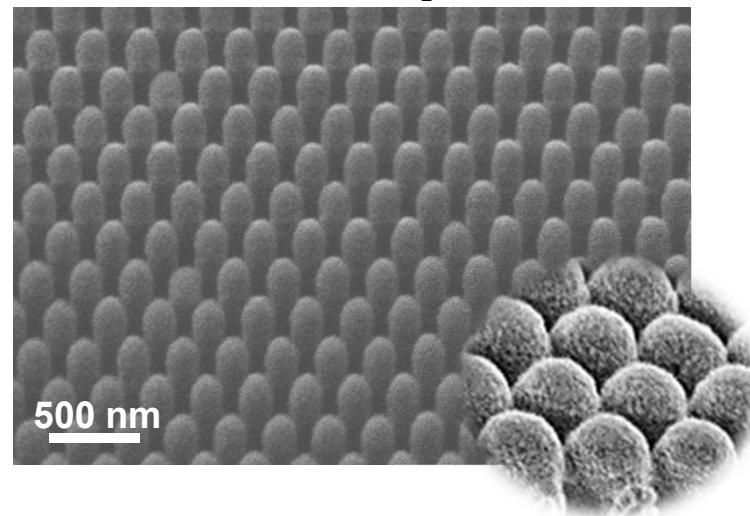
MAGNETRON SPUTTERING



PMMA-AR

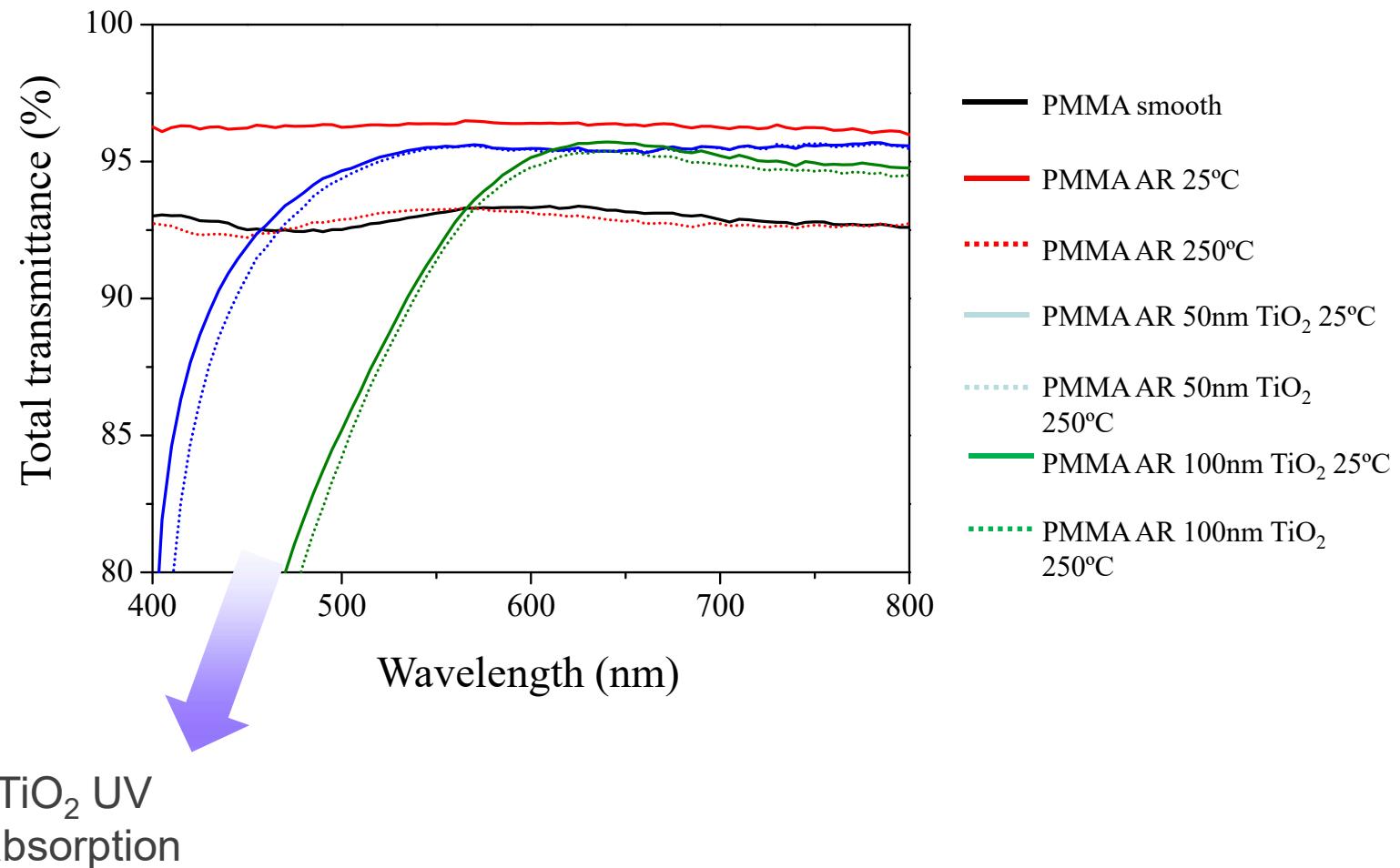


PMMA-AR-100nm-TiO₂



Daniel Fernandes
Tomas Kubart

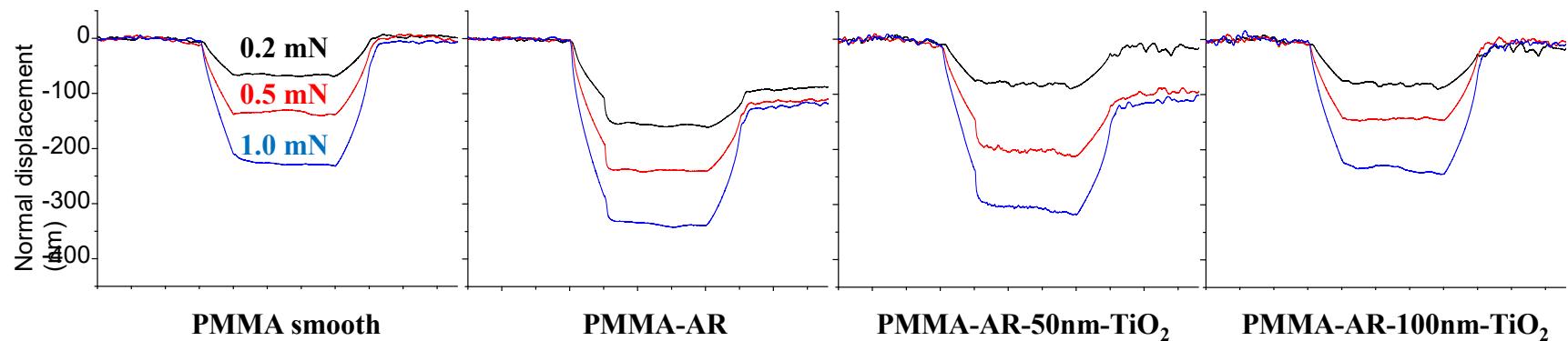
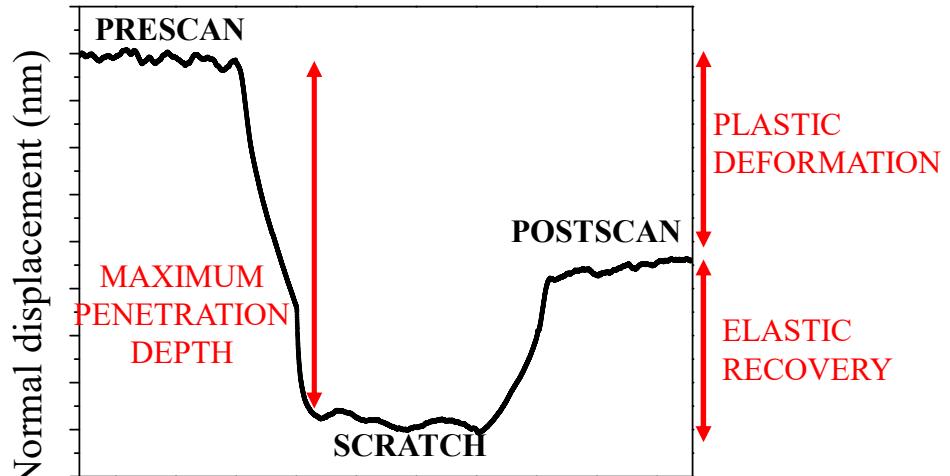
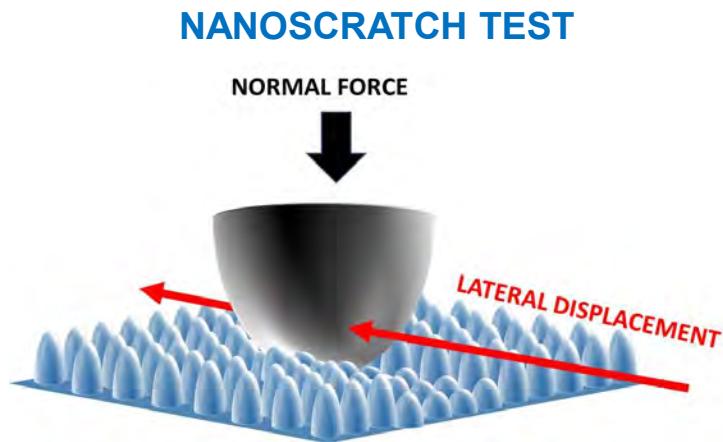
Optical transmittance



ANTIREFLECTIVE FUNCTIONALITY IS PRESERVED AT T>>T_g

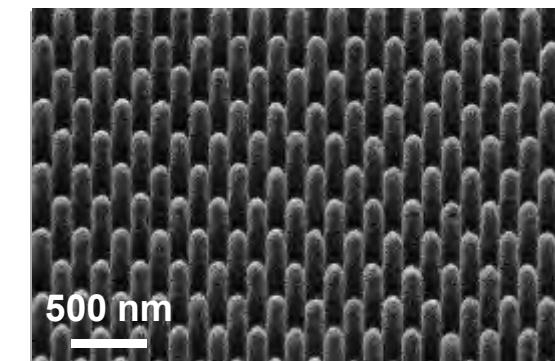
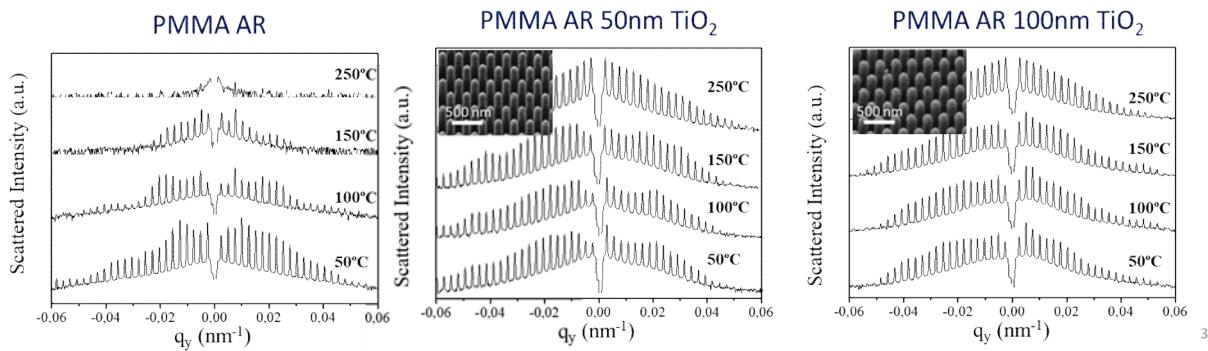
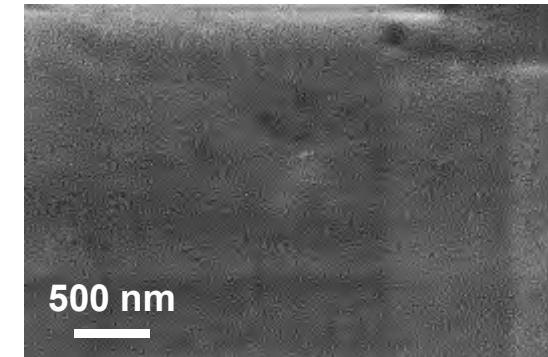
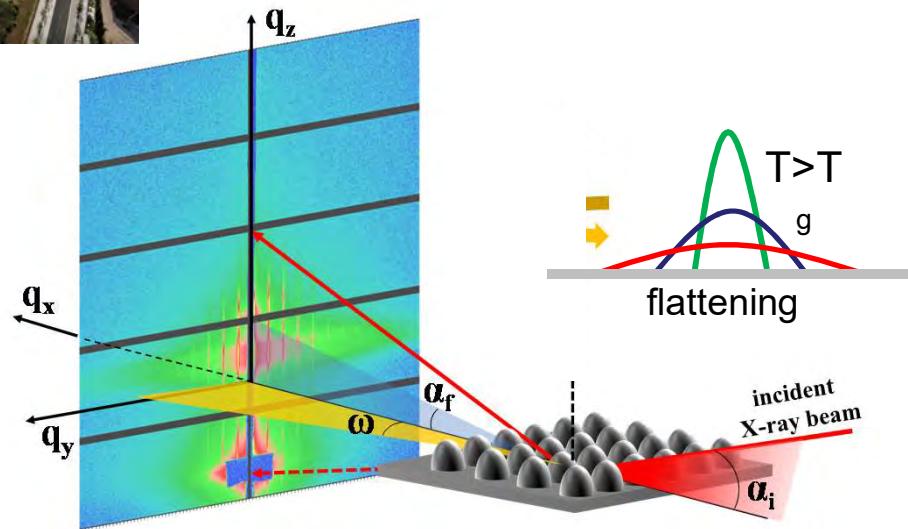
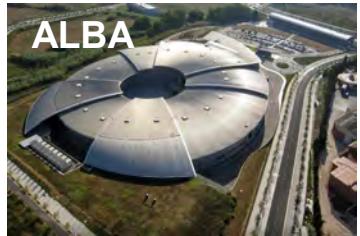
Mechanical resistance

Nanolito 26-27th January 2022



TiO₂ ENCAPSULATION IMPROVES SCRATCH RESISTANCE OF AR NANOSTRUCTURES

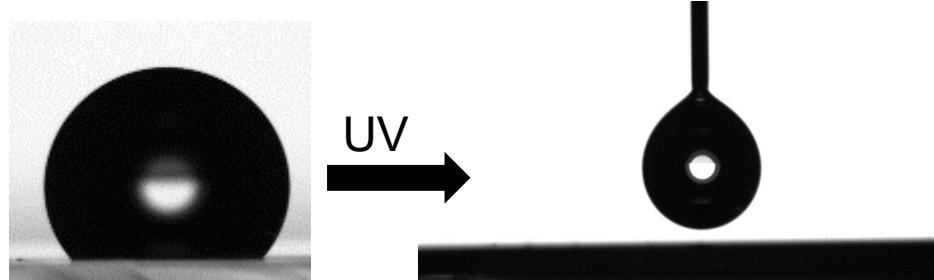
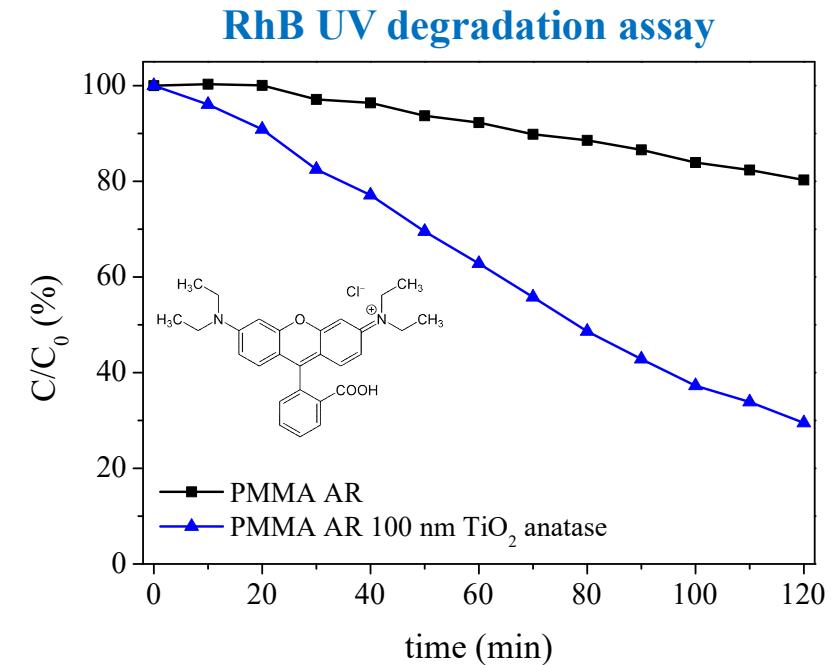
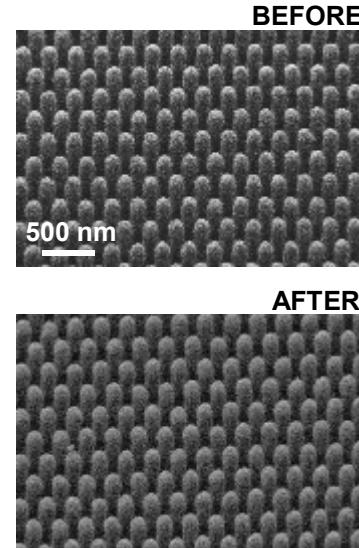
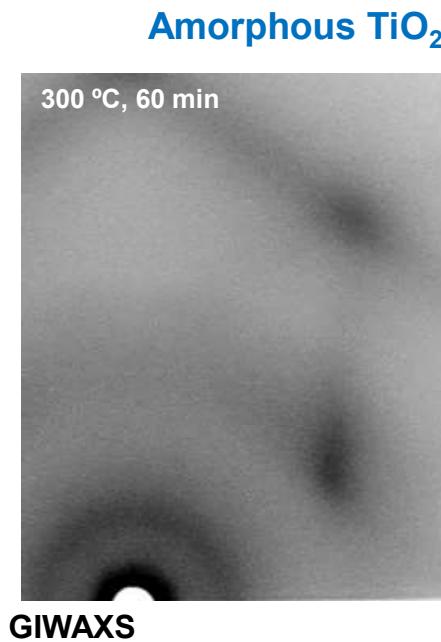
Thermal resistance



32

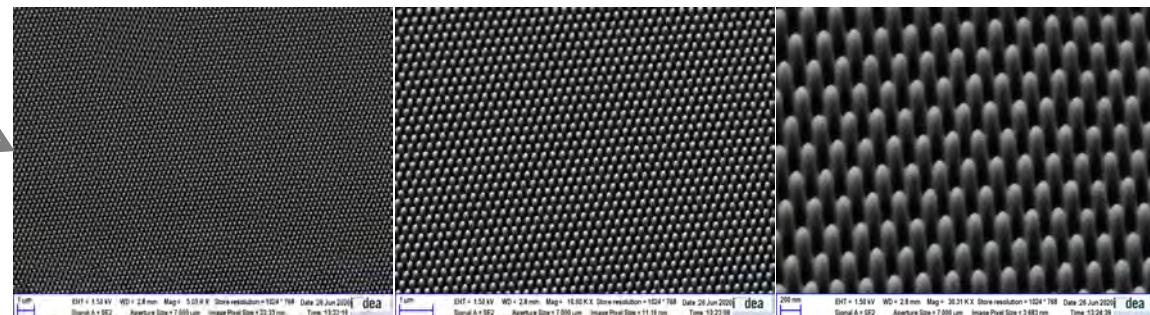
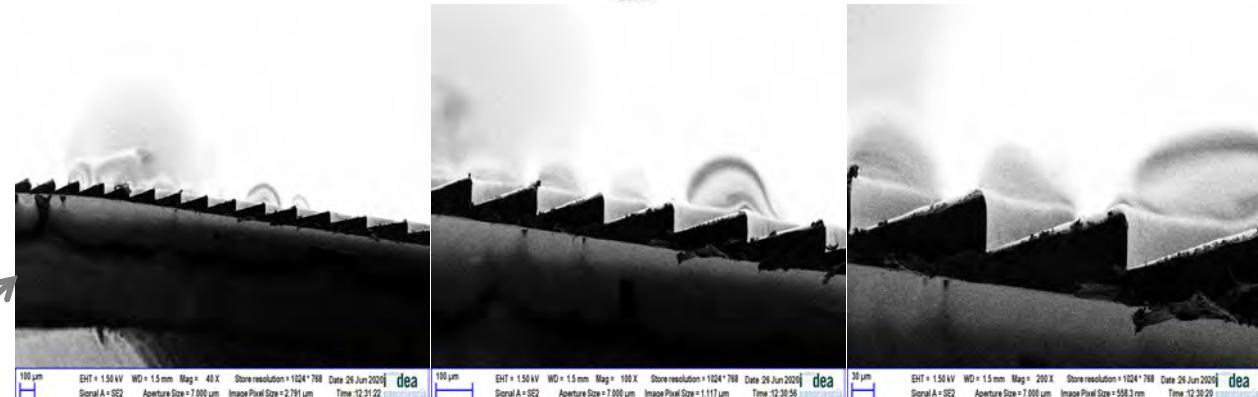
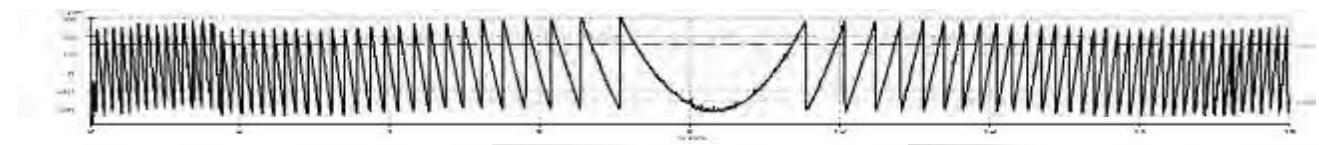
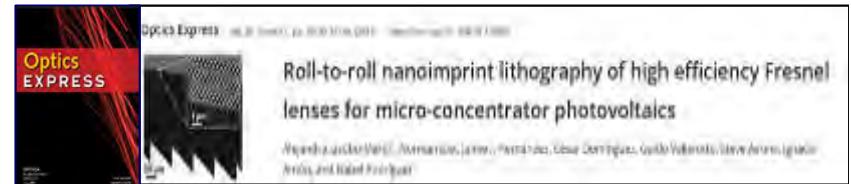
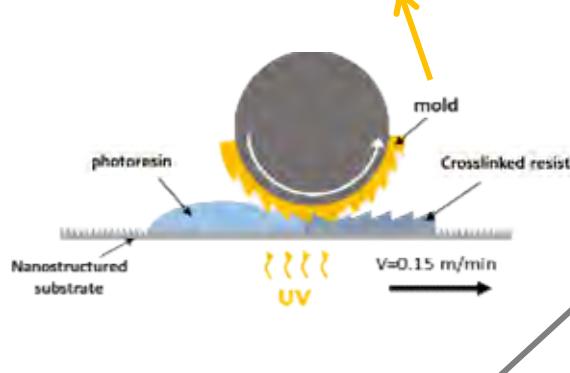
TiO₂ ENCAPSULATION PREVENTS REFLOW AND DISTORTION EFFECTS up to 250 C

Photoinduced self-cleaning



POLLUTANT DEGRADATION + SUPERHYDROPHYLICITY = SELF-CLEANING

UV R2R NIL Fresnel lens with anti-reflective moth eye



Acknowledgements

Group members

Jaime Hernandez
Alberto Martín Asensio
Miguel Esteban Lucía
Sergio Dávila
Maria Teresa Alameda



Alejandra Jacobo
Jean Cacheux
Ivan Navarro Baena



Collaborators



UPPSALA
UNIVERSITET

Daniel Fernandes
Tomas Kubart



Manuel R Osorio
Daniel Granados



Miguel Monclús
Jon Molina



César Domínguez
Ignacio Antón



Eduardo Solano
Juan Carlos Martínez

Thank you for your attention !

